Am29C116/116-1/116-2

16-Bit CMOS Microprocessors

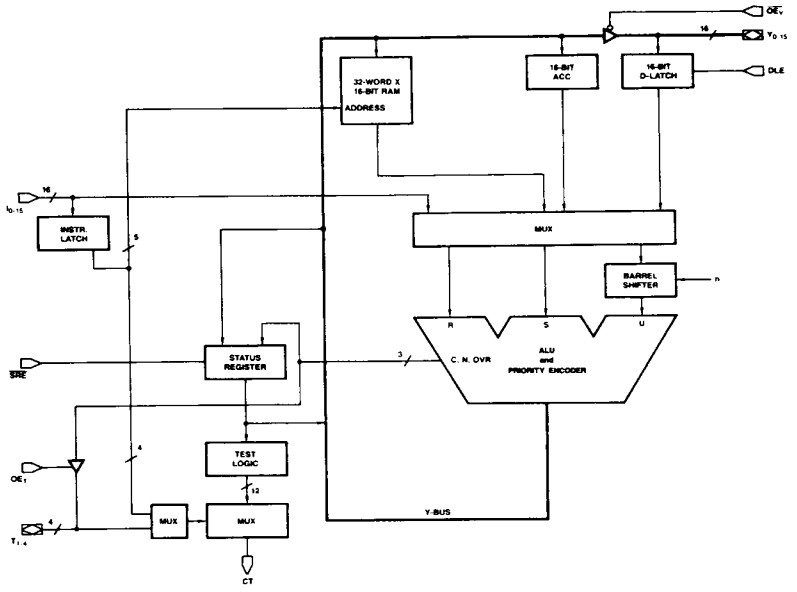
DISTINCTIVE CHARACTERISTICS

- **Am29C116**
  Supports up to 100-ns system cycle time. Less than 1-watt power dissipation and equivalent performance to the bipolar Am29116.
- **Am29C116-1**
  Faster, speed-select version of the Am29C116 (90 ns).
- **Am29C116-2**
  Can operate with 80-ns clock cycle.
- **Pin-Compatible and Functionally Equivalent to the Am29116**
  The architecture, instruction set, and pin-out are completely identical to the bipolar Am29116.
- **Optimized for High-Performance Controllers**
  The architecture is optimized for controllers providing an excellent solution for applications requiring bit-manipulation power.
- **Powerful Field Insertion/Extraction and Bit-Manipulation Instructions**
  Rotate-and-Merge, Rotate-and-Compare and bit-manipulation instructions provided for complex bit control.
- **Immediate Instruction Capability**
  May be used for storing constants in microcode or for configuring a second data port.
- **16-Bit Barrel Shifter**
- **32-Working Registers**

GENERAL DESCRIPTION

The Am29C116 is a microprogrammable 16-bit CMOS microprocessor whose architecture and instruction set is optimized for high-performance peripheral controllers, like graphics controllers, disk controllers, communications controllers, front-end concentrators and modems. The device also performs well in microprogrammed processor applications, especially when combined with the Am29C517A, 16 x 16 Multiplier. In addition to its complete arithmetic and logic instruction set, the Am29C116 instruction set contains functions particularly useful in controller applications; bit set, bit reset, bit test, rotate-and-merge, rotate-and-compare, and cyclic-redundancy-check (CRC) generation.

SIMPLIFIED BLOCK DIAGRAM*



BD001963

*For a detailed block diagram, refer to Figure 2.

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Issue Date: **March 1988**

RELATED AMD PRODUCTS

Part No.	Description
Am29C10A	CMOS 12-Bit Sequencer
Am29C111	CMOS 16-Bit Microsequencer
Am29114	8-Level Real-Time Interrupt Controller
Am29117	2-Port 16-Bit Microprocessor
Am29C117	CMOS Version of Am29117
Am29118	8-Bit Am29C116 I/O Support
Am29130	16-Bit Barrel Shifter
Am29PL131	64 x 32 Field-Programmable Controller
Am29PL141	64 x 32 Field-Programmable Controller
Am29CPL141	CMOS Version of Am29PL141
Am29PL142	128 x 32 Field-Programmable Controller
Am29CPL144	CMOS 512 x 32 Field-Programmable Controller
Am29C331	CMOS 16-Bit Microsequencer
Am29C516A	CMOS 16 x 16 Multiplier
Am29C517A	CMOS 2-Port 16 x 16 Multiplier

The following diagram (Figure 1) is a summary of devices within the Am29116 Family, showing performance versus power.

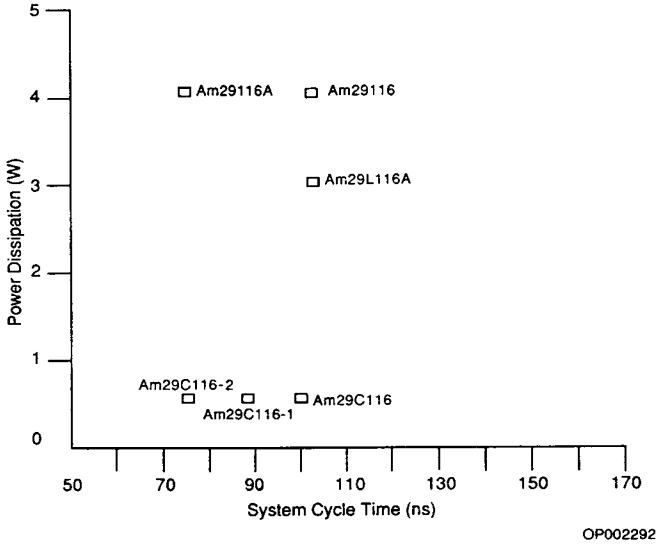
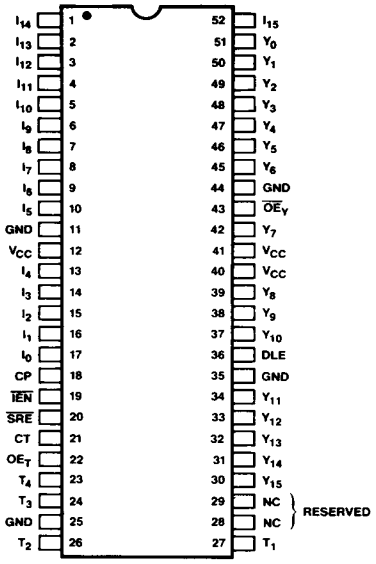


Figure 1. Am29116 Family (Performance vs. Power)

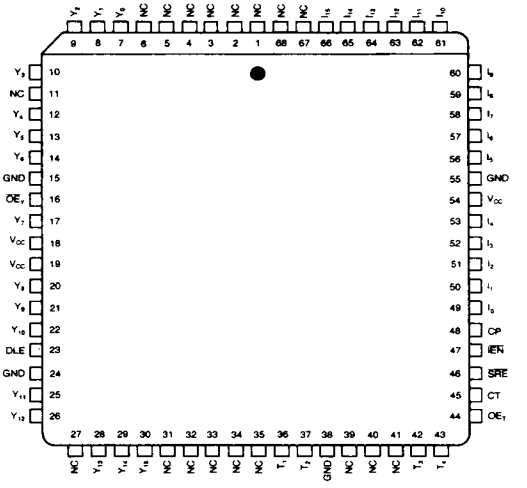
CONNECTION DIAGRAMS
Top View

DIPs



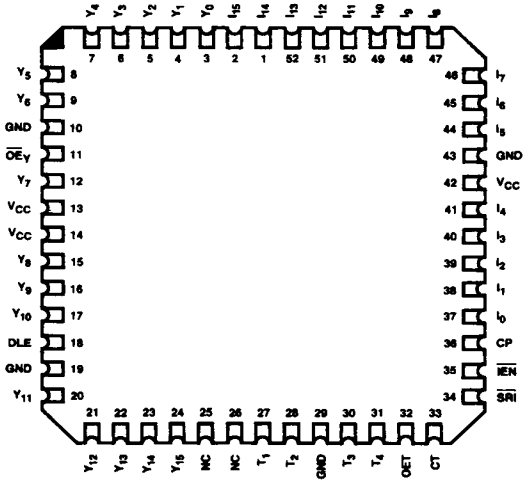
CD004190

PLCC



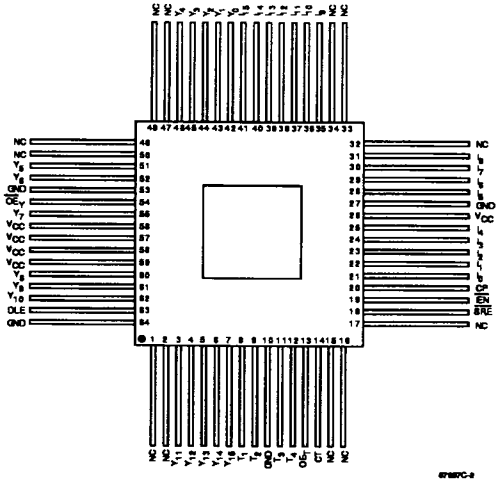
CD009470

LCC



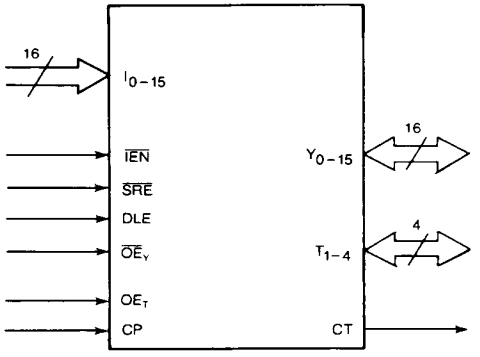
CD004180

Flatpack



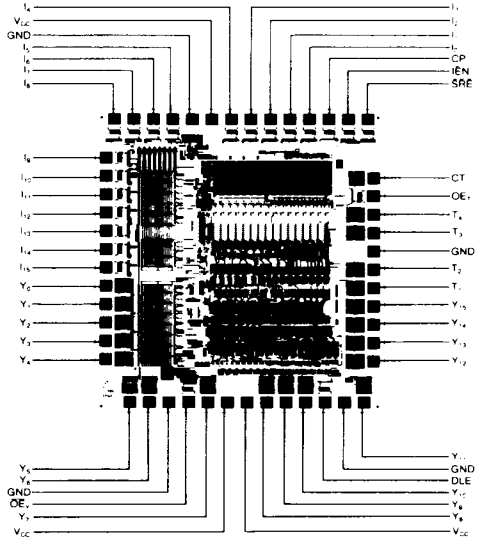
Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



LS002254

METALLIZATION AND PAD LAYOUT

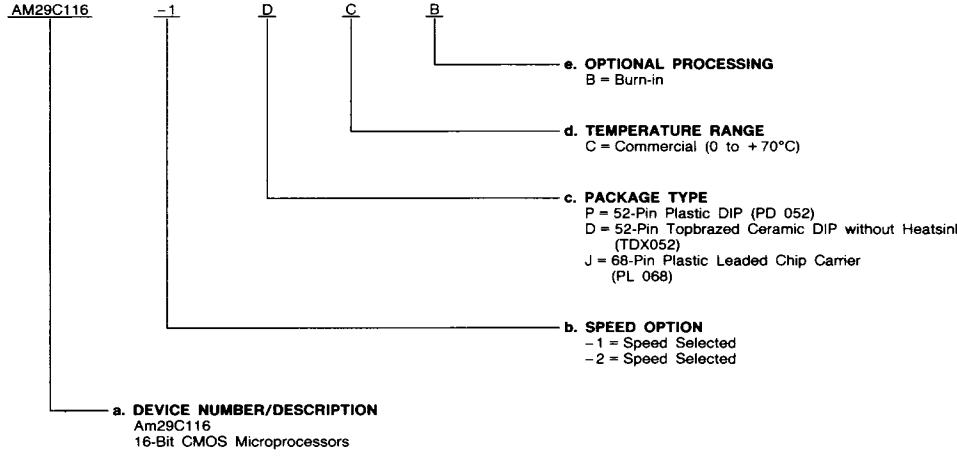


Die Size: 0.169" x 0.179"
Component Count: 14,000

ORDERING INFORMATION
Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:

a. Device Number
b. Speed Option (if applicable)
c. Package Type
d. Temperature Range
e. Optional Processing



Valid Combinations	
AM29C116	PC, PCB, DC, DCB, JC
AM29C116-1	
AM29C116-2	

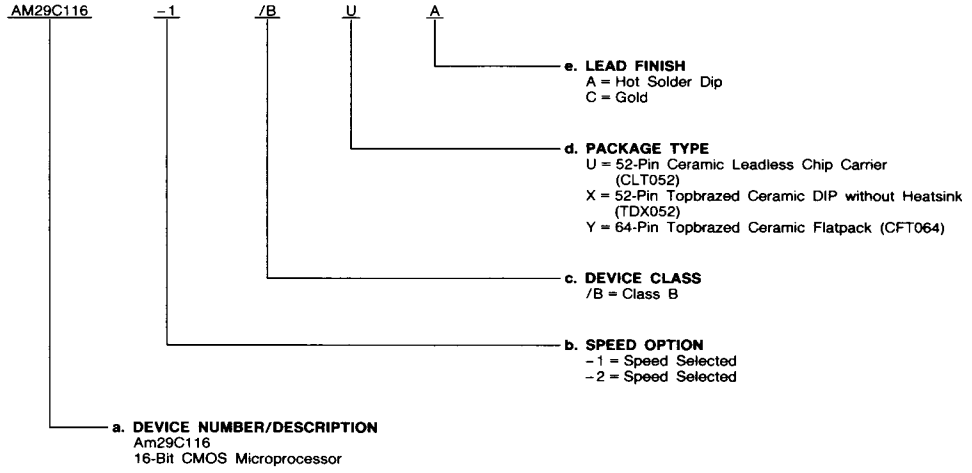
Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released valid combinations, and to obtain additional data on AMD's standard military grade products.

ORDERING INFORMATION (Cont'd.)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: **a. Device Number**
b. Speed Option (if applicable)
c. Device Class
d. Package Type
e. Lead Finish



Valid Combinations	
AM29C116	/BUA, /BXC, /BYC
AM29C116-1	
AM29C116-2	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups
1, 2, 3, 7, 8, 9, 10, 11

PIN DESCRIPTION

CP Clock Pulse (Input)
The clock input to the Am29C116. The RAM latch is transparent when the clock is HIGH. When the clock goes LOW, the RAM output is latched. Data is written into the RAM during the low period of the clock provided $\overline{IEN}$ is LOW and if the instruction being executed designates the RAM as the destination of operation. The Accumulator and Status Register will accept data on the LOW-HIGH transition of the clock if $\overline{IEN}$ is also LOW. The instruction latch becomes transparent when it exits an immediate instruction mode during a LOW-HIGH transition of the clock.

CT Conditional Test (Output)
The condition code multiplexer selects one of the twelve condition code signals and places them on the CT output. A HIGH on the CT output indicates a passed condition and a LOW indicates a failed condition.

DLE Data Latch Enable (Input)
When DLE is HIGH, the 16-bit data latch is transparent and is latched when DLE is LOW.

$\overline{IEN}$ Instruction Enable (Input)
With $\overline{IEN}$ LOW, data can be written into the RAM when the clock is LOW. The Accumulator can accept data during the LOW-HIGH transition of the clock. Having $\overline{IEN}$ LOW, the Status Register can be updated when $\overline{SRE}$ is LOW. With $\overline{IEN}$ HIGH, the conditional test output, CT, is disabled as a function of the instruction inputs. $\overline{IEN}$ should be LOW for the first half of the first cycle of an immediate instruction.

$I_0 - I_{15}$ Instruction Inputs — 16 (Input)
Used to select the operations to be performed in the Am29C116. Also used as data inputs while performing immediate instructions.

OE_T Output Enable (Input)
When OE_T is LOW, the 4-bit T outputs are disabled (high-impedance); when OE_T is HIGH, the 4-bit T outputs are enabled (HIGH or LOW).

$\overline{OE}_Y$ Output Enable (Input)
When $\overline{OE}_Y$ is HIGH, the 16-bit Y outputs are disabled (high-impedance); when $\overline{OE}_Y$ is LOW, the 16-bit Y outputs are enabled (HIGH or LOW).

$\overline{SRE}$ Status Register Enable (Input)
When $\overline{SRE}$ and $\overline{IEN}$ are both LOW, the Status Register is updated at the end of all instructions with the exception of NO-OP, Save Status, and Test Status. Having either $\overline{SRE}$ or $\overline{IEN}$ HIGH will inhibit the Status Register from changing.

$T_1 - T_4$ Input/Output Pins — 4 (Input/Output)
Under the control of OE_T, the four lower status bits Z, C, N, OVR, become outputs on T_1-T_4, respectively, when OE_T goes HIGH. When OE_T is LOW, T_1-T_4 are used as inputs to generate the CT output.

$Y_0 - Y_{15}$ Data I/O Lines — 16 (Input/Output)
When $\overline{OE}_Y$ is HIGH, Y_0-Y_{15} are used as external data inputs which allow data to be directly loaded into the 16-bit data latch. Having $\overline{OE}_Y$ LOW allows the ALU data to be output on Y_0-Y_{15}.

FUNCTIONAL DESCRIPTION

The following diagram (Figure 2) shows a detailed block diagram of the Am29C116.

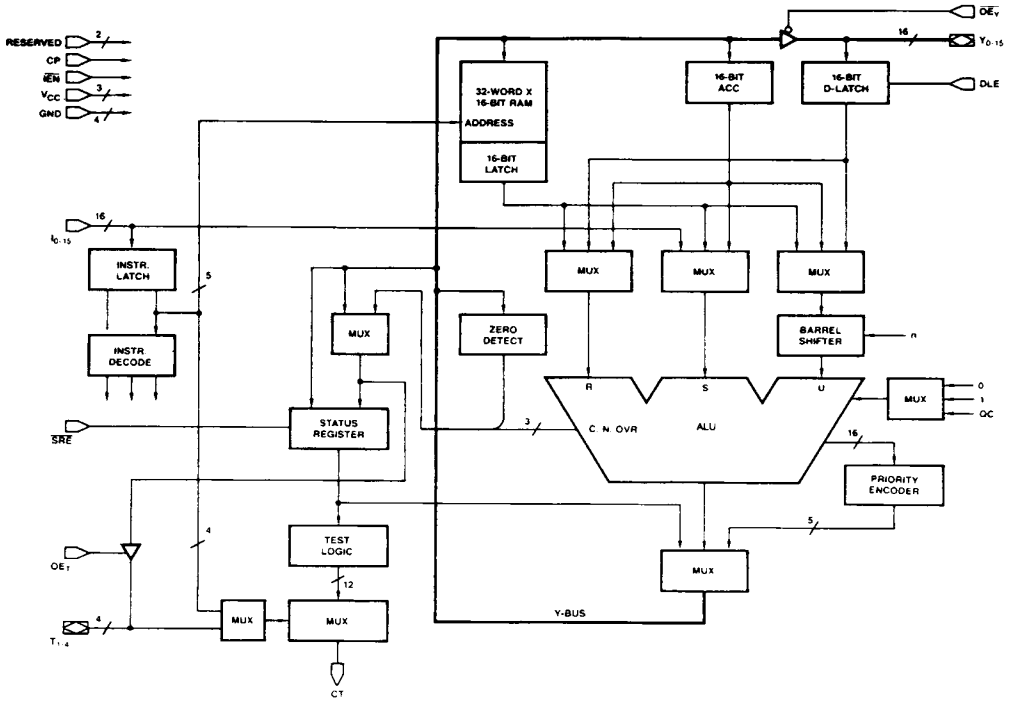


Figure 2. Detailed Am29C116 Block Diagram

Architecture of the Am29C116

The Am29C116 is a high-performance, microprogrammable 16-bit CMOS microprocessor.

As shown in the Block Diagrams, the device consists of the following elements interconnected with 16-bit data paths.

- 32-Word by 16-Bit RAM
- Accumulator
- Data Latch
- Barrel Shifter
- ALU
- Priority Encoder
- Status Register
- Condition-Code Generator/Multiplexer
- Three-State Output Buffers
- Instruction Latch and Decoder

32-Word by 16-Bit RAM

The 32-Word by 16-Bit RAM is a single-port RAM with a 16-bit latch at its output. The latches are transparent when the clock input (CP) is HIGH and latched when the clock input is LOW. Data is written into the RAM while the clock is LOW if the $\overline{IEN}$ input is also LOW and if the instruction being executed defines the RAM as the destination of the operation. For byte instructions, only the lower eight RAM bits are written into; for word instructions, all 16 bits are written into. With the use of an external multiplexer on five of the instruction inputs, it is possible to select separate read and write addresses for the same instruction. This two-address operation is not allowed for immediate instructions.

Accumulator

The 16-bit Accumulator is an edge-triggered register. The Accumulator accepts data on the LOW-to-HIGH transition of the clock input if the $\overline{IEN}$ input is LOW and if the instruction being executed defines the Accumulator as the destination of the operation. For byte instructions, only the lower eight bits of the Accumulator are written into; for word instructions, all 16 bits are written into.

Data Latch

The 16-bit Data Latch holds the data input to the Am29C116 on the bi-directional Y bus. The latch is transparent when the DLE input is HIGH and latched when the DLE input is LOW.

Barrel Shifter

A 16-bit Barrel Shifter is used as one of the ALU inputs. This permits rotating data from either the RAM, the Accumulator or the Data Latch up to 15 positions. In the word mode, the Barrel Shifter rotates a 16-bit word; in the byte mode, it rotates only the lower eight bits.

Arithmetic Logic Unit

The Am29C116 contains a 16-bit ALU with full carry lookahead across all 16 bits in the arithmetic mode. The ALU is capable of operating on either one, two or three operands, depending upon the instruction being executed. It has the ability to execute all conventional one and two operand operations, such as pass, complement, two's complement, add, subtract, AND, NAND, OR, NOR, EXOR, and EX-NOR. In addition, the ALU can also execute three-operand instructions such as rotate and merge and rotate and compare with mask. All ALU operations can be performed on either a word or byte basis, byte operations being performed on the lower eight bits only.

The ALU produces three status outputs, C (carry), N (negative) and OVR (overflow). The appropriate flags are generated at the byte or word level, depending upon whether the device is executing in the byte or word mode. The Z (zero) flag, although not generated by the ALU, detects zero at both the byte and word level.

The carry input to the ALU is generated by the Carry Multiplexer which can select an input of zero, one, or the stored carry bit from the Status Register, QC. Using QC as the carry input allows execution of multiprecision addition and subtractions.

Priority Encoder

The Priority Encoder produces a binary-weighted code to indicate the locations of the highest order ONE at its input. The input to the Priority Encoder is generated by the ALU which performs an AND operation on the operand to be prioritized and a mask. The mask determines which bit locations to eliminate from prioritization. In the word mode, if no bit is HIGH, the output is a binary zero. If bit 15 is HIGH, the output is a binary one. Bit 14 produces a binary two, etc. Finally, if only bit 0 is HIGH, a binary 16 is produced.

In the byte mode, bits 8 thru 15 do not participate. If none of bits 7 thru 0 are HIGH, the output is a binary zero. If bit 7 is HIGH a binary one is produced. Bit 6 produces a binary two, etc. Finally, if only bit 0 is HIGH, a binary 8 is produced.

Status Register

The Status Register holds the 8-bit status word. With the Status-Register Enable, ($\overline{SRE}$) input LOW and the $\overline{IEN}$ input LOW, the Status Register is updated at the end of all instructions except NO-OP, Save-Status and Test-Status instructions. $\overline{SRE}$ going HIGH or $\overline{IEN}$ going HIGH inhibits the Status Register from changing.

The lower four bits of the Status Register contain the ALU status bits of Zero (Z), Carry (C), Negative (N), and Overflow (OVR). The upper four bits contain a Link bit and three user-definable status bits (Flag 1, Flag 2, Flag 3).

With $\overline{SRE}$ LOW and $\overline{IEN}$ LOW, the lower four status bits are updated after each instruction except those mentioned above, NO-OP, Save Status, Status Test and the Status Set/Reset instruction for the upper four bits. Under the same conditions, the upper four status bits are changed only during their respective Status Set/Reset instructions and during Status Load instructions in the word mode. The Link-Status bit is also updated after each shift instruction.

The Status Register can be loaded from the internal Y-bus, and can also be selected as a source for the internal Y-bus. When the Status Register is loaded in the word mode, all 8-bits are updated; in the byte mode, only the lower 4 bits (Z, C, N, OVR) are updated.

When the Status Register is selected as a source in the word mode, all eight bits are loaded into the lower byte of the destination; the upper byte of the destination is loaded with all zeros. In the byte mode, the Status Register again loads into the lower byte of the destination, but the upper byte remains unchanged. This Store and Load combination allows saving and restoring the Status Register for interrupt and subroutine processing. The four lower status bits (Z, C, N, OVR) can be read directly via the bidirectional T bus. These four bits are available as outputs on the $T_{1\text{-}4}$ outputs whenever OE_T is HIGH.

Condition-Code Generator/Multiplexer

The Condition-Code Generator/Multiplexer contains the logic necessary to develop the 12 condition-code test signals. The multiplexer portion can select one of these test signals and place it on the CT output for use by the microprogram sequence. The multiplexer may be addressed in two different ways. One way is through the Test Instruction. This instruction specifies the test condition to be placed in the CT output, but

does not allow an ALU operation at the same time. The second method uses the bidirectional T bus as an input. This requires extra bits in the microword, but provides the ability to simultaneously test and execute. The test instruction lines, I_{0-4}, have priority over T_{1-4}, for testing status.

Three-State Output Buffers

There are two sets of Three-State Output Buffers in the Am29C116. One set controls the bidirectional, 16-bit Y bus. These outputs are enabled by placing a LOW on the $\overline{OE}$ input. A HIGH puts the Y outputs in the high-impedance state, allowing data to be input to the Data latch from an external source.

The second set of Three-State Output Buffers controls the bidirectional 4-bit T bus and is enabled by placing a HIGH on the OE_T input. This allows storing the four internal ALU status bits (Z, C, N, OVR) externally. A LOW OE_T input forces the T outputs into the high-impedance state. External devices can then drive the T bus to select a test condition for the CT output.

Instruction Latch and Decoder

The 16-bit Instruction Latch is normally transparent to allow decoding of the Instruction Inputs by the Instruction Decoder into the internal control signals for the Am29C116. All instructions except Immediate Instructions are executed in a single clock cycle.

Immediate instructions require two clock cycles for execution. During the first clock cycle, the Instruction Decoder recognizes that an Immediate Instruction is being specified and captures the data on the Instruction Inputs in the Instruction Latch. During the second clock cycle, the data on the Instruction Inputs is used as one of the operands for the function specified during the first clock cycle. At the end of the second clock cycle, the Instruction Latch is returned to its transparent state.

Instruction Set

The instruction set of the Am29C116 is very powerful. In addition to the single and two operand logical and arithmetic instructions, the Am29C116 instruction set contains functions particularly useful in controller applications: bit set, bit reset, bit test, rotate and merge, rotate and compare, and cyclic-redundancy-check (CRC) generation. Complex instructions like rotate and merge, rotate and compare, and prioritize are executed in a single microcycle.

Three data types are supported by the Am29C116.

- Bit
- Byte
- Word (16-bit)

In the byte mode, data is written into the lower half of the word and the upper half is unchanged. The special case is when the status register is specified as the destination. In the byte mode, the LSH (OVR, N, C, Z) of the status register is updated and in the word mode all eight bits of the status register are updated. The status register does not change for save status and test status instructions. In the test status instructions, the CT output has the result and the Y-bus is undefined.

The Am29C116 Instruction Set can be divided into eleven types of instructions. These are:

- Single Operand
- Two Operand
- Single Bit Shift
- Rotate and Merge
- Bit Oriented
- Rotate by n Bits
- Rotate and Compare
- Prioritize
- Cyclic-Redundancy-Check
- Status
- No-Op

Each instruction type is arbitrarily divided into quadrants. Two of the sixteen instruction lines decode to four quadrants labelled from 0 to 3. The quadrants were defined mainly for convenience in classification of the instruction set and addressing modes and can be used together with the OP CODES to distinguish the instructions.

The following pages describe each of the instruction types in detail. Throughout the description $\overline{OE}_Y$ is assumed to be LOW allowing ALU outputs on the Y-bus.

Table 1 illustrates operand source-destination combinations for each instruction type.

TABLE 1. OPERAND SOURCE DESTINATION COMBINATIONS

Instruction Type	Operand Combinations (Note 1)		
	Source (R/S)		Destination
Single Operand	RAM (Note 2) ACC D D(0E) D(SE) I 0		RAM ACC Y Bus Status ACC and Status
	Source (R)	Source (S)	Destination
Two Operand	RAM RAM D D ACC D	ACC I RAM ACC I I	RAM ACC Y Bus Status ACC and Status
	Source (U)		Destination
Single Bit Shift	RAM ACC ACC D D D		RAM ACC Y Bus RAM ACC Y Bus
	Source (U)		Destination
Rotate n Bits	RAM ACC D		RAM ACC Y Bus
	Source (R/S)		Destination
Bit Oriented	RAM ACC D		RAM ACC Y Bus
	Rotated Source (U)	Mask (S)	Non-Rotated Source/ Destination (R)
Rotate and Merge	D D D D ACC RAM	I RAM I ACC I I	ACC ACC RAM RAM RAM ACC

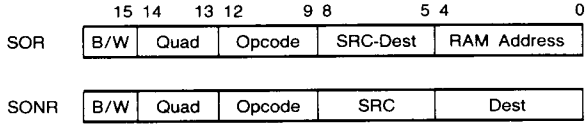
Instruction Type	Operand Combinations (Note 1)		
	Rotated Source (U)	Mask (S)	Non-Rotated Source/ Destination (R)
Rotate and Compare	D D D RAM	I I ACC I	 RAM RAM ACC
	Source (R)	Mask (S)	Destination
Prioritize (Note 3)	RAM ACC D	RAM ACC I 0	RAM ACC Y Bus
	Data In	Destination	Polynomial
Cyclic Redundancy Check	QLINK	RAM	ACC
No Operation	-		
	Bits Affected		
Set Reset Status	OVR, N, C, Z LINK Flag1 Flag2 Flag3		
	Source		Destination
Store Status	Status		RAM ACC Y Bus
	Source (R)	Source (S)	Destination
Status Load	D ACC D	ACC I I	Status Status and ACC
	Test Condition (CT)		
Test Status	(N⊕OVR) + Z N⊕OVR Z OVR Low C $Z + \overline{C}$ N LINK Flag 1 Flag 2 Flag 3		

Notes: 1. When there is no dividing line between the R&S OPERAND or SOURCE and DESTINATION, the two must be used as a given pair. But where there exists such a separation, any combination of them is possible.
2. In the SINGLE OPERAND INSTRUCTION, RAM cannot be used when both ACC and STATUS are designated as a DESTINATION.
3. In the PRIORITIZE INSTRUCTION, OPERAND and MASK must be different sources.

SINGLE OPERAND INSTRUCTIONS

The Single Operand Instructions contain four indicators: byte or word mode, opcode, source and destination. They are further subdivided into two types. The first type uses RAM as a source or destination or both, and the second type does not use RAM as a source or destination. Both types have different instruction formats as shown below. Under the control of instruction inputs, the desired function is performed on the source and the result is either stored in the specified destination or placed on the Y-bus or both. For a special case where 8-bit to 16-bit conversion is needed, the Am29C116 is capable of extending sign bit (D(SE)) or binary zero (D(0E)) over 16-bits in the word mode. The least significant four bits of the Status Register (OVR, N, C, Z) are affected by the function performed in this category. The most significant bits of status register (FLAG1, FLAG2, FLAG3, LINK) are not affected. The only limitation in this type is that the RAM cannot be used as a source when both ACC and the Status Register are specified as a destination.

SINGLE OPERAND FIELD DEFINITIONS



SINGLE OPERAND INSTRUCTION

I5 I4 I3 I2 9 8 5 4 0

Instruction[1]	B/W[2]	Quad[3]	Opcode			R/S[4]	Dest[4]		RAM Address		
SOR	0 = B 1 = W	10	1100 MOVE $\overline{SRC}$ → Dest 1101 COMP $\overline{SRC}$ → Dest 1110 INC $\overline{SRC}$ + 1 → Dest 1111 NEG $\overline{SRC}$ + 1 → Dest			0000 SORA 0010 SORY 0011 SORS 0100 SOAR 0110 SODR 0111 SOIR 1000 SOZR 1001 SOZER 1010 SOSER 1011 SORR	RAM RAM RAM ACC D I 0 D(0E) D(SE) RAM	ACC Y Bus Status RAM RAM RAM RAM RAM RAM RAM	00000 R00 RAM Reg 00 .. .. 11111 R31 RAM Reg 31		

Instruction	B/W	Quad	Opcode			R/S[4]		Destination		
SONR	0 = B 1 = W	11	1100 MOVE $\overline{SRC}$ → Dest 1101 COMP $\overline{SRC}$ → Dest 1110 INC $\overline{SRC}$ + 1 → Dest 1111 NEG $\overline{SRC}$ + 1 → Dest			0100 SOA 0110 SOD 0111 SOI 1000 SOZ 1001 SOZE 1010 SOSE	ACC D I 0 D(0E) D(SE)	00000 NRY 00001 NRA 00100 NRS 00101 NRAS	Y Bus ACC Status[5] ACC, Status[5]	

Notes:
1. The instruction mnemonic designates different instruction formats used in the Am29C116. They are useful in microcode assembly.
2. B = Byte Mode, W = Word Mode.
3. See Instruction Set description.
4. R = Source; S = Source; Dest = Destination.
5. When status is destination,
   Status i ← Yi i = 0 to 3 (Byte mode)
   i = 0 to 7 (Word mode)

Y BUS AND STATUS – SINGLE OPERAND INSTRUCTIONS

Instruction	Opcode	Description	B/W	Y — Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
SOR SONR	MOVE	SRC → Dest	0 = B 1 = W	Y ← SRC	NC	NC	NC	NC	0	U	0	U
	COMP	$\overline{SRC}$ → Dest		Y ← $\overline{SRC}$	NC	NC	NC	NC	0	U	0	U
	INC	SRC +1 → Dest		Y ← SRC +1	NC	NC	NC	NC	U	U	U	U
	NEG	$\overline{SRC}$ +1 → Dest		Y ← $\overline{SRC}$ +1	NC	NC	NC	NC	U	U	U	U

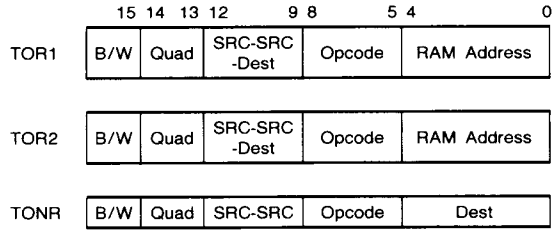
SRC = Source
U = Update
NC = No Change

0 = Reset
1 = Set
i = 0 to 15 when not specified

TWO OPERAND INSTRUCTIONS

The Two Operand Instructions contain five indicators: byte or word mode, opcode, R source, S source, and destination. They are further subdivided into two types. The first type uses RAM as the source and/or destination and the second type does not use RAM as source or destination. The first type has two formats; the only difference is in the quadrant. Under the control of instruction inputs, the desired function is performed on the specified sources and the result is stored in the specified destination or placed on the Y-bus or both. The least significant four bits of the status register (OVR, N, C, Z) are affected by the arithmetic functions performed and only the N and Z bits are affected by the logical functions performed. The OVR and C bits of the status register are forced to ZERO for logical functions. Add with carry and Subtract with carry instructions are useful for Multiprecision Add or Subtract.

TWO OPERAND FIELD DEFINITIONS



TWO OPERAND INSTRUCTIONS

Instruction	B/W	Quad			R[1]	S[1]	Dest[1]	Opcode			RAM Address		
TOR1	0 = B 1 = W	00	0000 0010 0011 1000 1010 1011 1100 1110 1111	TORAA TORIA TODRA TORAY TORIY TODRY TORAR TORIR TODRR	RAM RAM D RAM RAM D RAM RAM D	ACC I RAM ACC I RAM ACC I RAM	ACC ACC ACC Y Bus Y Bus Y Bus RAM RAM RAM	0000 0001 0010 0011 0100 0101 0110 0111 1000 1001 1010 1011	SUBR SUBRC[2] SUBS SUBSC[2] ADD ADDC AND NAND EXOR NOR OR EXNOR	S minus R S minus R with carry R minus S R minus S with carry R plus S R plus S with carry $\overline{R \cdot S}$ $\overline{R \cdot S}$ $\overline{R \oplus S}$ $\overline{R + S}$ $\overline{R + S}$ $\overline{R \oplus S}$	00000 . . 11111	R00 . . R31	RAM Reg 00 . . . . RAM Reg 31
Instruction	**B/W**	**Quad**			**R[1]**	**S[1]**	**Dest[1]**	**Opcode**			**RAM Address**		
TOR2	0 = B 1 = W	10	0001 0010 0101	TODAR TOAIR TODIR	D ACC D	ACC I I	RAM RAM RAM	0000 0001 0010 0011 0100 0101 0110 0111 1000 1001 1010 1011	SUBR SUBRC[2] SUBS SUBSC[2] ADD ADDC AND NAND EXOR NOR OR EXNOR	S minus R S minus R with carry R minus S R minus S with carry R plus S R plus S with carry $\overline{R \cdot S}$ $\overline{R \cdot S}$ $\overline{R \oplus S}$ $\overline{R + S}$ $\overline{R + S}$ $\overline{R \oplus S}$	00000 . . 11111	R00 . . R31	RAM Reg 00 . . . . RAM Reg 31

Note 1: R = Source
S = Source
Dest = Destination
Note 2: During subtraction the carry is interpreted as $\overline{\text{borrow}}$.

TWO OPERAND INSTRUCTIONS

Instruction	B/W	Quad	R[1]	S[1]	Opcode			Destination		
TONR	0 = B 1 = W	11	0001 TODA 0010 TOAI 0101 TODI	D ACC ACC I D I	0000 SUBR 0001 SUBRC 0010 SUBS 0011 SUBSC 0100 ADD 0101 ADDC 0110 AND 0111 NAND 1000 EXOR 1001 NOR 1010 OR 1011 EXNOR	S minus R S minus R with carry R minus S R minus S with carry R plus S R plus S with carry $\underline{R \cdot S}$ $R \cdot S$ $\underline{R \oplus S}$ $R + S$ $\underline{R + S}$ $\overline{R \oplus S}$	00000 NRY 00001 NRA 00100 NRS 00101 NRAS	Y Bus ACC Status[2] ACC, Status[2]	

Notes 1: R = Source
S = Source
2: When status is destination,
Status $i \leftarrow Y_i$ i = 0 to 3 (Byte mode)
i = 0 to 7 (Word mode)
3: During subtraction the carry is interpreted as $\overline{\text{borrow}}$.
4: OVR = $C_8 \oplus C_7$ (Byte mode)
OVR = $C_{16} \oplus C_{15}$ (Word mode)

Y BUS AND STATUS CONTENTS – TWO OPERAND INSTRUCTIONS

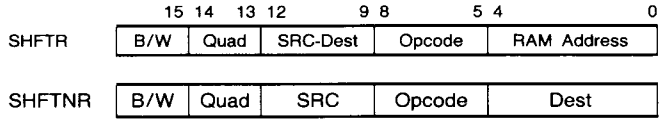
Instruction	Opcode	Description	B/W	Y – Bus	Flag3	Flag2	Flag 1	LINK	OVR	N	C	Z
TOR1 TOR2 TONR	SUBR	S minus R	0 = B 1 = w	$Y \leftarrow S + \overline{R} + 1$	NC	NC	NC	NC	U	U	U	U
	SUBRC	S minus R with carry		$Y \leftarrow S + \overline{R} + QC$	NC	NC	NC	NC	U	U	U	U
	SUBS	R minus S		$Y \leftarrow R + \overline{S} + 1$	NC	NC	NC	NC	U	U	U	U
	SUBSC	R minus S with carry		$Y \leftarrow R + \overline{S} + QC$	NC	NC	NC	NC	U	U	U	U
	ADD	R plus S		$Y \leftarrow R + S$	NC	NC	NC	NC	U	U	U	U
	ADDC	R plus S with carry		$Y \leftarrow R + S + QC$	NC	NC	NC	NC	U	U	U	U
	AND	$R \cdot S$		$Y \leftarrow R_i$ AND S_i	NC	NC	NC	NC	0	U	0	U
	NAND	$\overline{R \cdot S}$		$Y_i \leftarrow R_i$ NAND S_i	NC	NC	NC	NC	0	U	0	U
	EXOR	$R \oplus S$		$Y_i \leftarrow R_i$ EXOR S_i	NC	NC	NC	NC	0	U	0	U
	NOR	$\overline{R + S}$		$Y_i \leftarrow R_i$ NOR S_i	NC	NC	NC	NC	0	U	0	U
	OR	$R + S$		$Y_i \leftarrow R_i$ OR S_i	NC	NC	NC	NC	0	U	0	U
	EXNOR	$\overline{R \oplus S}$		$Y_i \leftarrow R_i$ EXNOR S_i	NC	NC	NC	NC	0	0	0	U

U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

SINGLE BIT SHIFT INSTRUCTIONS

The Single Bit Shift Instructions contain four indicators: byte or word mode, direction and shift linkage, source and destination. They are further subdivided into two types. The first type uses RAM as the source and/or destination and the second type does not use RAM as source or destination. Under the control of the instruction inputs, the desired shift function is performed on the specified source and the result is stored in the specified destination or placed on the Y-bus or both. The direction and shift linkage indicator defines the direction of the shift (up or down) as well as what will be shifted into the vacant bit. On a shift-up instruction, the LSB may be loaded with ZERO, ONE, or the Link-Status bit (QLINK). The MSB is loaded into the Link-Status bit as shown in Figure 3. On a shift-down instruction, the MSB may be loaded with ZERO, ONE, the contents of the Status Carry flip-flop, (QC), the Exclusive-OR of the Negative-Status bit and the Overflow-Status bit (QN ⊕ QOVR) or the Link-Status bit. The LSB is loaded into the Link-Status bit as shown in Figure 4. The N and Z bits of the Status register are affected but the OVR and C bits are forced to ZERO. The Shift-Down with QN ⊕ QOVR is useful for Two's Complement multiplication.

SINGLE BIT SHIFT FIELD DEFINITIONS:



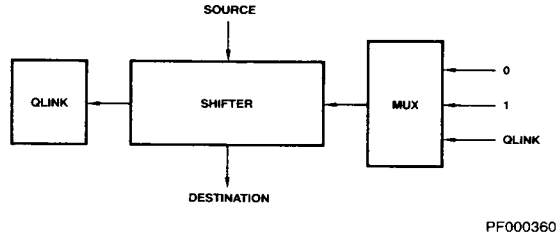


Figure 3. Shift Up Function

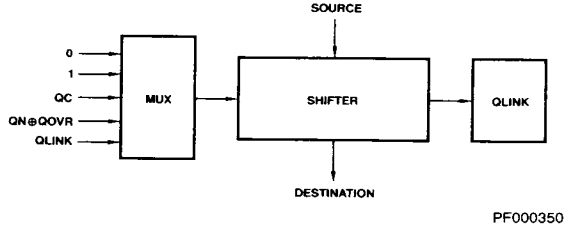


Figure 4. Shift Down Function

SINGLE BIT SHIFT INSTRUCTIONS

SINGLE BIT SHIFT

Instruction	B/W	Quad	U[1]		Dest[1]	Opcode			RAM Address		
SHFTR	0 = B 1 = W	10	0110 0111	SHRR SHDR	RAM D	RAM RAM	0000 0001 0010 0100 0101 0110 0111 1000	SHUPZ SHUP1 SHUPL SHDNZ SHDN1 SHDNL SHDNC SHDNOV	Up Up Up Down Down Down Down Down	0 1 QLINK 0 1 QLINK QC QN⊕QOVR	00000 . . . 11111	R00 . . . R31	RAM Reg 00 . . . . . RAM Reg 31

Instruction	B/W	Quad	U[1]			Opcode				Destination		
SHFTNR	0 = B 1 = W	11	0110 0111	SHA SHD	ACC D	0000 0001 0010 0100 0101 0110 0111 1000	SHUPZ SHUP1 SHUPL SHDNZ SHDN1 SHDNL SHDNC SHDNOV	Up Up Up Down Down Down Down Down	0 1 QLINK 0 1 QLINK QC QN⊕QOVR	00000 00001	NRY NRA	Y Bus ACC

Note 1. U = Source
Dest = Destination

Y BUS AND STATUS – SINGLE BIT SHIFT INSTRUCTIONS

Instruction	Opcode	Description	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
SHR SHNR	SHUPZ SHUP1 SHUPL	Up 0 Up 1 Up QLINK	1 = W	$Y_i \leftarrow SRC_{i-1}$, i = 1 to 15; $Y_0 \leftarrow$ Shift Input	NC	NC	NC	SRC_{15}*	0	SRC_{14}	0	U
			0 = B	$Y_i \leftarrow SRC_{i-1}$, i = 1 to 7; $Y_0 \leftarrow$ Shift Input; $Y_8 \leftarrow SRC_7$, $Y_i \leftarrow SRC_{i-9}$ for i = 9 to 15	NC	NC	NC	SRC_7*	0	SRC_6	0	U
	SHDNZ SHDN1 SHDNL SHDNC SHCNOV	Down 0 Down 1 Down QLINK Down QC Down QN⊕QOVR	1 = W	$Y_i \leftarrow SRC_{i+1}$, i = 0 to 14; $Y_{15} \leftarrow$ Shift Input	NC	NC	NC	SRC_0*	0	Shift Input	0	U
			0 = B	$Y_i \leftarrow SRC_{i+1}$, i = 0 to 6; $Y_i \leftarrow SRC_{i-7}$, i = 8 to 14; $Y_{7,15} \leftarrow$ Shift Input	NC	NC	NC	SRC_0*	0	Shift Input	0	U

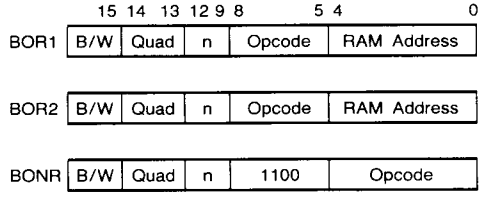
SRC = Source
U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

*Shifted Output is loaded into the QLINK.

BIT ORIENTED INSTRUCTIONS

The Bit Oriented Instructions contain four indicators: byte or word mode, operation, source/destination, and the bit position of the bit to be operated on (Bit 0 is the least significant bit). They are further subdivided into two types. The first type uses the RAM as both source and destination and has two kinds of formats which differ only by quadrant. The second type does not use the RAM as a source or a destination. Under the control of the instruction inputs, the desired function is performed on the specified source and the result is stored in the specified destination or placed on the Y-bus or both. The operations which can be performed are: Set Bit n which forces the n^{th} bit to a ONE leaving other bits unchanged; Reset Bit n which forces the n^{th} bit to ZERO leaving the other bits unchanged; Test Bit n, which sets the ZERO Status Bit depending on the state of bit n leaving all the bits unchanged; Load 2^n, which loads ONE in Bit position n and ZERO in all other bit positions; Load $\overline{2^n}$ which loads ZERO in bit position n and ONE in all other bit positions; increment by 2^n, which adds 2^n to the operand; and decrement by 2^n which subtracts 2^n from the operand. For all the Load, Set, Reset and Test instructions, the N and Z bits are affected and OVR and C bit of the Status register are forced to ZERO. For all arithmetic instructions the LSH (OVR, C, N, Z bits) of the Status register is affected.

BIT ORIENTED FIELD DEFINITIONS



BIT ORIENTED INSTRUCTIONS

Instruction	B/W	Quad	n	Opcode			RAM Address		
BOR1	0 = B 1 = W	11	0 to 15	1101 1110 1111	SETNR RSTNR TSTNR	Set RAM, bit n Reset RAM, bit n Test RAM, bit n	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**	**n**	**Opcode**			**RAM Address**		
BOR2	0 = B 1 = W	10	0 to 15	1100 1101 1110 1111	LD2NR LDC2NR A2NR S2NR	$2^n \rightarrow$ RAM $\overline{2^n} \rightarrow$ RAM RAM plus $2^n \rightarrow$ RAM RAM minus $2^n \rightarrow$ RAM	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**	**n**				**Opcode**		
BONR	0 = B 1 = W	11	0 to 15	1100			00000 00001 00010 00100 00101 00110 00111 10000 10001 10010 10100 10101 10110 10111	TSTNA RSTNA SETNA A2NA S2NA LD2NA LDC2NA TSTND RSTND SETND A2NDY S2NDY LS2NY LDC2NY	Test ACC, bit n Reset ACC, bit n Set ACC, bit n ACC plus $2^n \rightarrow$ ACC ACC minus $2^n \rightarrow$ ACC $2^n \rightarrow$ ACC $\overline{2^n} \rightarrow$ ACC Test D, bit n Reset D, bit n Set D, bit n D plus $2^n \rightarrow$ Y BUS D minus $2^n \rightarrow$ Y Bus $2^n \rightarrow$ Y Bus $\overline{2^n} \rightarrow$ Y Bus

BIT ORIENTED INSTRUCTIONS

Y BUS AND STATUS – BIT ORIENTED INSTRUCTIONS

Instruction	Opcode	Description	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
BOR1	SETNR	Set RAM Bit n	0 = B	$Y_i \leftarrow RAM_i$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	RSTNR	Reset RAM, Bit n	1 = W	$Y_i \leftarrow RAM_i$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	U
	TSTNR	Test Ram, Bit n		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow SRC_n$	NC	NC	NC	NC	0	U	0	U
BOR2	LD2NR	$2^n \rightarrow$ RAM		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	LDC2NR	$\overline{2^n} \rightarrow$ RAM		$Y_i \leftarrow 1$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	0
	A2NR	RAM + $2^n \rightarrow$ RAM		$Y \leftarrow RAM + 2^n$	NC	NC	NC	NC	U	U	U	U
	S2NR	RAM – $2^n \rightarrow$ RAM		$Y \leftarrow RAM - 2^n$	NC	NC	NC	NC	U	U	U	U
BONR	TSTNA	Test ACC, Bit n		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow ACC_n$	NC	NC	NC	NC	0	U	0	U
	RSTNA	Reset ACC, Bit n		$Y_i \leftarrow ACC_i$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	U
	SETNA	Set ACC, Bit n		$Y_i \leftarrow ACC_i$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	A2NA	ACC + $2^n \rightarrow$ ACC		$Y \leftarrow ACC + 2^n$	NC	NC	NC	NC	U	U	U	U
	S2NA	ACC – $2^n \rightarrow$ ACC		$Y \leftarrow ACC - 2^n$	NC	NC	NC	NC	U	U	U	U
	LD2NA	$2^n \rightarrow$ ACC		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	LDC2NA	$\overline{2^n} \rightarrow$ ACC		$Y_i \leftarrow 1$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	0
	TSTND	Test D, Bit n		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow D_n$	NC	NC	NC	NC	0	U	0	U
	RSTND	Reset D, Bit n*		$Y_i \leftarrow D_i$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	U
	SETND	Set D, Bit n*		$Y_i \leftarrow D_i$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	A2NDY	D + $2^n \rightarrow$ Y Bus		$Y \leftarrow D + 2^n$	NC	NC	NC	NC	U	U	U	U
	S2NDY	D – $2^n \rightarrow$ Y Bus		$Y \leftarrow D - 2^n$	NC	NC	NC	NC	U	U	U	U
	LD2NY	$2^n \rightarrow$ Y Bus		$Y_i \leftarrow 0$ for $i \neq n$; $Y_n \leftarrow 1$	NC	NC	NC	NC	0	U	0	0
	LDC2NY	$\overline{2^n} \rightarrow$ Y Bus		$Y_i \leftarrow 1$ for $i \neq n$; $Y_n \leftarrow 0$	NC	NC	NC	NC	0	U	0	0

SRC = Source
U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

*Destination is not D Latch but Y Bus.

ROTATE BY n BITS INSTRUCTIONS

The Rotate by n Bits Instructions contain four indicators: byte or word mode, source, destination and the number of places the source is to be rotated. They are further subdivided into two types. The first type uses RAM as a source and/or a destination and the second type does not use RAM as a source or destination. The first type has two different formats and the only difference is in the quadrant. The second type has only one format as shown in the table. Under the control of instruction inputs, the n indicator specifies the number of bit positions the source is to be rotated up (0 to 15), and the result is either stored in the specified destination or placed on the Y bus or both. An example of this instruction is given in Figure 5. In the Word mode, all 16-bits are rotated up; while in the Byte mode, only the lower 8-bits (0-7) are rotated up. In the Word mode, a rotate up by n bits is equivalent to a rotate down by (16-n) bits. Similarly, in the Byte mode a rotate up by n bits is equivalent to a rotate down by (8-n) bits. The N and Z bits of the Status Register are affected and OVR and C bits are forced to ZERO.

EXAMPLE: n = 4, Word Mode

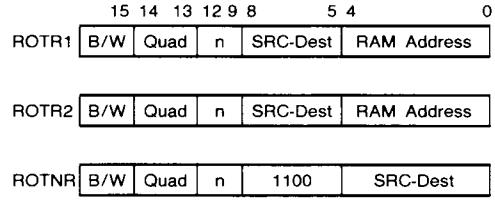
Source	0001	0011	0111	1111
Destination	0011	0111	1111	0001

EXAMPLE: n = 4, Byte Mode

Source	0001	0011	0111	1111
Destination	0001	0011	1111	0111

Figure 5. Rotate by n Example

ROTATE BY n BITS FIELD DEFINITIONS



ROTATE BY n BITS INSTRUCTIONS

Instruction	B/W	Quad	n			U[1]	Dest[1]	RAM Address		
ROTR1	0 = B 1 = W	00	0 to 15	1100 1110 1111	RTRA RTRY RTRR	RAM RAM RAM	ACC Y Bus RAM	00000 . . . 11111	R00 . . . R31	RAM Reg 00 . . . RAM Reg 31
Instruction	**B/W**	**Quad**	**n**			**U[1]**	**Dest[1]**	**RAM Address**		
ROTR2	0 = B 1 = W	01	0 to 15	0000 0001	RTAR RTDR	ACC D	RAM RAM	00000 . . . 11111	R00 . . . R31	RAM Reg 00 . . . RAM Reg 31
Instruction	**B/W**	**Quad**	**n**					**U[1]**	**Dest[1]**	
ROTNR	0 = B 1 = W	11	0 to 15	1100				11000 11001 11100 11101	RTDY RTDA RTAY RTAA	D D ACC ACC	Y Bus ACC Y Bus ACC

Note 1: U = Source
Dest = Destination

Y BUS AND STATUS - ROTATE BY n BITS INSTRUCTIONS

Instruction	Op-code	B/W	Y - Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
ROTR1 ROTR2 ROTNR		1 = W	$Y_i \leftarrow SRC_{(i-n) \bmod 16}$	NC	NC	NC	NC	0	SRC_{15-n}	0	U
		0 = B	$Y_i \leftarrow SRC_{i+8} = SRC_{(i-n) \bmod 8}$ for i = 0 to 7	NC	NC	NC	NC	0	SRC_{8-n}	0	U

SRC = Source
U = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

ROTATE AND MERGE INSTRUCTION

The Rotate and Merge Instructions contain five indicators: byte or word mode, rotated source, non-rotated source/destination, mask and the number of bit positions a source is to be rotated. The function performed by the Rotate and Merge instruction is illustrated in Figure 6. The rotated source, U, is rotated up by the Barrel Shifter n places. The mask input then selects, on a bit by bit basis, the rotated U input or R input. A ZERO in bit i of the mask will select the i^{th} bit of the R input as the i^{th} output bit, while ONE in bit i will select the i^{th} rotated U input as the output bit. The output word is stored in the non-rotated operand location. The N and Z bits are affected. The OVR and C bits of the Status register are forced to ZERO. An example of this instruction is given in Figure 7.

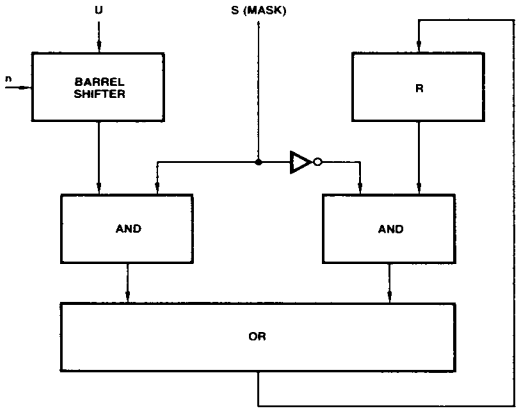


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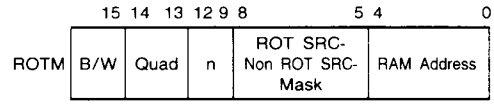
Figure 6. Rotate and Merge Function

ROTATE AND MERGE FIELD DEFINITIONS:



EXAMPLE: n = 4, Word Mode

U	0011	0001	0101	0110
Rotated U	0001	0101	0110	0011
R	1010	1010	1010	1010
Mask (S)	0000	1111	0000	1111
Destination	1010	0101	1010	0011

Figure 7. Rotate and Merge Example

ROTATE AND MERGE INSTRUCTION

Instruction	B/W	Quad	n			U[1]	R/Dest[1]	S[1]	RAM Address		
ROTM	0 = B 1 = W	01	0 to 15	0111	MDAI	D	ACC	I	00000	R00	RAM Reg 00
				1000	MDAR	D	ACC	RAM	..	..	....
				1001	MDRI	D	RAM	I	11111	R31	RAM Reg 31
				1010	MDRA	D	RAM	ACC			
				1100	MARI	ACC	RAM	I			
				1110	MRAI	RAM	ACC	I			

Note 1. U = Rotated Source
R/Dest = Non-Rotated Source and Destination
S = Mask

Y BUS AND STATUS – ROTATED MERGE

Instruction	Opcode	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
ROTM		1=W	$Y_i \leftarrow (\text{Non Rot Op})_i \cdot \overline{(\text{mask})_i} + (\text{Rot Op})_{(i-n) \bmod 16} \cdot (\text{mask})_i$	NC	NC	NC	NC	0	U	0	U
		0 = B	$Y_i \leftarrow (\text{Non Rot Op})_i \cdot \overline{(\text{mask})_i} + (\text{Rot Op})_{(i-n) \bmod 8} \cdot (\text{mask})_i$	NC	NC	NC	NC	0	U	0	U

U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

ROTATE AND COMPARE INSTRUCTIONS

The Rotate and Compare Instructions contain five indicators: byte or word mode, rotated source, non-rotated source, mask, and the number of bit positions the rotated source is to be rotated up. Under the control of instruction inputs, the function performed by the Rotate and Compare instruction is illustrated in Figure 8. The rotated operand is rotated by the Barrel Shifter n places. The mask is inverted and ANDed on a bit-by-bit basis with the output of the Barrel Shifter and R input. Thus, a ONE in the mask input eliminates that bit from the comparison. A ZERO allows the comparison. If the comparison passes, the Zero flag is set. If it fails, the Zero flag is reset. The N and Z bit are affected. The OVR and C bits of the Status register are forced to ZERO. An example of this instruction is given in Figure 9.

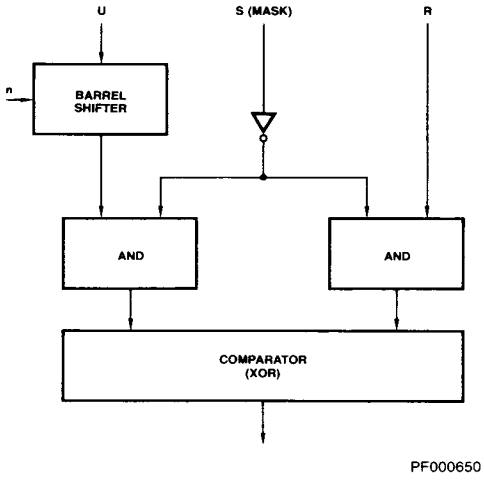
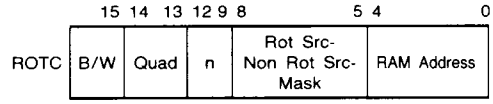


Figure 8. Rotate and Compare Function

ROTATE AND COMPARE FIELD DEFINITIONS



EXAMPLE: n = 4, Word Mode

U	0011	0001	0101	0110
U Rotated	0001	0101	0110	0011
R	0001	0101	1111	0000
Mask (S)	0000	0000	1111	1111

Z (status) = 1

Figure 9. Rotate and Compare Examples

ROTATE AND COMPARE INSTRUCTIONS

Instruction	B/W	Quad	n			U[1]	R[1]	S[1]	RAM Address		
ROTC	0=B 1 = W	01	0 to 15	0010 0011 0100 0101	CDAI CDRI CDRA CRAI	D D D RAM	ACC RAM RAM ACC	I I ACC I	00000 .. 11111	R00 .. R31	RAM Reg 00 ... RAM Reg 31

Note 1. U = Rotated Source
R = Non-Rotated Source
S = Mask

Y BUS AND STATUS - ROTATE AND COMPARE

Instruction	Opcode	B/W	Y - Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
ROTC		1 = W	$Y_i \leftarrow (\text{Non Rot Op})_i \cdot \overline{(\text{mask})_i} \oplus (\text{Rot Op})_{(i-n) \bmod 16} \cdot \overline{(\text{mask})_i}$	NC	NC	NC	NC	0	U	0	U
		0 = B	$Y_i \leftarrow (\text{Non Rot Op})_i \cdot \overline{(\text{mask})_i} \oplus (\text{Rot Op})_{(i-n) \bmod 8} \cdot \overline{(\text{mask})_i}$	NC	NC	NC	NC	0	U	0	U

U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

PRIORITIZE INSTRUCTION

The Prioritize Instructions contain four indicators: byte or word mode, operand source (R), mask source (S) and destination. They are further subdivided into two types. The function performed by the Prioritize instruction is shown in Figure 10. The R operand is ANDed with the complement of the Mask operand. A ZERO in the Mask operand allows the corresponding bit in the R operand to participate in the priority encoding function. A ONE in the Mask operand forces the corresponding bit in the R operand to a ZERO, eliminating it from participation in the priority encoding function.

The priority encoder accepts a 16-bit input and produces a 5-bit binary-weighted code indicating the bit position of the highest priority active bit. If none of the inputs are active, the output is ZERO. In the Word mode, if input bit 15 is active, the output is 1, etc. Figure 11 lists the output as a function of the highest-priority active-bit position in both the Word and Byte mode. The N and Z bits are affected and the OVR and C bits of the status register are forced to ZERO. The only limitation in this instruction is that the operand and the mask must be different sources.

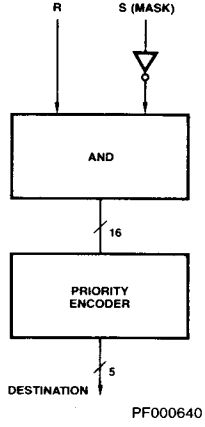
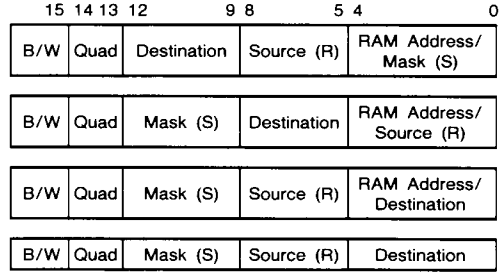


Figure 10. Prioritize Function

PRIORITIZE INSTRUCTION FIELD DEFINITIONS



WORD MODE		BYTE MODE*	
Highest Priority Active Bit	**Encoder Output**	**Highest Priority Active Bit**	**Encoder Output**
None	0	None	0
15	1	7	1
14	2	6	2
.	.	.	.
.	.	.	.
1	15	1	7
0	16	0	8

*Bits 8 through 15 do not participate.

Figure 11.

PRIORITIZE INSTRUCTION

Instruction	B/W	Quad	Destination			Source (R)			RAM Address/Mask (S)		
PRT1	0 = B 1 = W	10	1000 1010 1011	PRIA PR1Y PR1R	ACC Y Bus RAM	0111 1001	RPT1A PR1D	ACC D	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**	**Mask (S)**			**Destination**			**RAM Address/Source (R)**		
PRT2	0 = B 1 = W	10	1000 1010 1011	PRA PRZ PRI	Acc 0 I	0000 0010	PR2A PR2Y	ACC Y Bus	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**	**Mask (S)**			**Source (R)**			**RAM Address/Dest**		
PRT3	0 = B 1 = W	10	1000 1010 1011	PRA PRZ PRI	ACC 0 I	0011 0100 0110	PR3R PR3A PR3D	RAM ACC D	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**	**Mask (S)**			**Source (R)**			**Destination**		
PRTNR	0 = B 1 = W	11	1000 1010 1011	PRA PRZ PRI	ACC 0 I	0100 0110	PRTA PRTD	ACC D	00000 00001	NRY NRA	Y Bus ACC

Y BUS AND STATUS - PRIORITIZE INSTRUCTION

Instruction	Opcode	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
PRT1 PRT2		1 = W	$Y_i \leftarrow$ CODE ($SCR_n \cdot \overline{mask_n}$); $Y_m \leftarrow 0$; i = 0 to 4 and n = 0 to 15 m = 5 to 15	NC	NC	NC	NC	0	U	0	U
PRT3 PRTNR		0 = B	$Y_i \leftarrow$ CODE ($SCR_n \cdot \overline{mask_n}$); $Y_m \leftarrow 0$; i = 0 to 3 and n = 0 to 7 m = 4 to 15	NC	NC	NC	NC	0	U	0	U

SRC = Source NC = No Change 1 = Set
U = Update 0 = Reset i = 0 to 15 when not specified

CRC INSTRUCTION

The CRC (Cyclic-Redundancy-Check) Instructions contain one indicator: address of a RAM register to use as the check sum register. The CRC instruction provides a method for generation of the check bits in a CRC calculation. Two CRC instructions are provided – CRC Forward and CRC Reverse. The reason for providing two instructions is that CRC standards do not specify which data bit is to be transmitted first, the LSB or the MSB, but they do specify which check bit must be transmitted first. Figure 12 illustrates the method used to generate these check bits for the CRC Forward function and Figure 13 illustrates method used for the 2CRC Reverse function. The ACC serves as a polynomial mask to define the generating polynomial while the RAM register holds the partial result and eventually the calculated check sum. The LINK-bit is used as the serial input. The serial input combines with the MSB of the check-sum register, according to the polynomial defined by the polynomial mask register. When the last input bit has been processed, the check-sum register contains the CRC check bits. The LINK, N and Z bits are affected and the OVR and C bits of the Status register are forced to ZERO.

CYCLIC-REDUNDANCY-CHECK DEFINITIONS:

	15	14	13	12	9	8	5	4	0
CRCF	1	Quad	0110		0011		RAM Address		
CRCR	1	Quad	0110		1001		RAM Address		

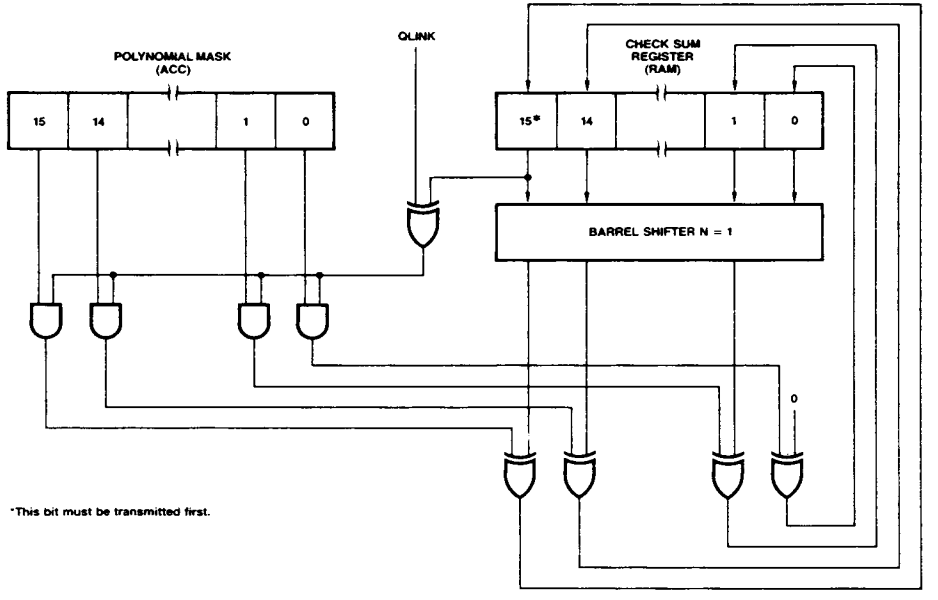


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Figure 12. CRC Forward Function

CRC INSTRUCTION

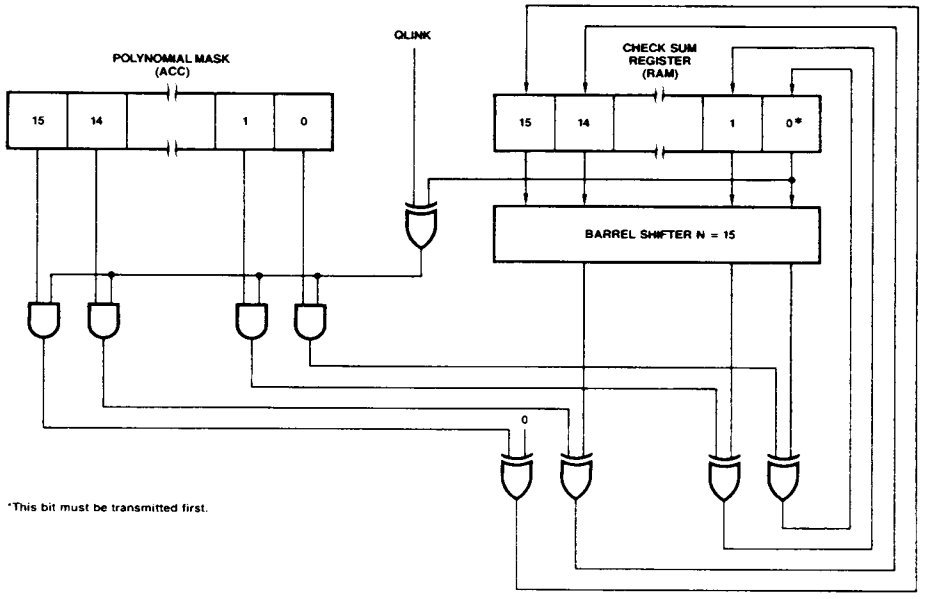

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Figure 13. CRC Reverse Function

CYCLIC REDUNDANCY CHECK

Instruction	B/W	Quad			RAM Address		
CRCF	1	10	0110	0011	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
Instruction	**B/W**	**Quad**			**RAM Address**		
CRCR	1	10	0110	1001	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31

Y BUS AND STATUS – CYCLIC REDUNDANCY CHECK

Instruction	Opcode	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
CRCF		1 = W	$Y_i \leftarrow [(QLINK \oplus RAM_{15}) \cdot ACC_i] \oplus RAM_{i-1}$ for i = 15 to 1 $Y_0 \leftarrow [(QLINK \oplus RAM_{15}) \cdot ACC_0] \oplus 0$	NC	NC	NC	RAM_{15}*	0	U	0	U
CRCR		1 = W	$Y_i \leftarrow [(QLINK \oplus RAM_0) \cdot ACC_i] \oplus RAM_{i+1}$ for i = 14 to 0 $Y_{15} \leftarrow [(QLINK \oplus RAM_0) \cdot ACC_{15}] \oplus 0$	NC	NC	NC	RAM_0*	0	U	0	U

*QLINK is loaded with the shifted out bit from the checksum register.

U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

STATUS INSTRUCTIONS

Status Instructions – The Set Status Instruction contains a single indicator. This indicator specifies which bit or group of bits, contained in the status register (Figure 14), are to be set (forced to a ONE).

7	6	5	4	3	2	1	0
Flag3	Flag2	Flag1	LINK	OVR	N	C	Z

MPR-775

Figure 14. Status Byte

The Reset Status Instruction contains a single indicator. This indicator specifies which bit or group of bits, contained in the status register, are to be reset (forced to ZERO).

The Store Status Instruction contains two indicators; byte/word and a second indicator that specifies the destination of the status register. The Store Status Instruction allows the status of the processor to be saved and restored later, which is an especially useful function for interrupt handling.

The status register is always stored in the lower byte of the RAM or the ACC register. Depending upon byte or word mode the upper byte is unchanged or loaded with all ZEROs respectively.

The Load Status instructions are included in the single operand and two operand instruction types.

The Test Status Instructions contain a single indicator which specifies which one of the 12 possible test conditions are to be placed on the Conditional-Test output. Besides the eight bits in the Status register (QZ, QC, QN, QOVR, QLINK, QFlag1, QFlag 2, and QFlag3), four logical functions (QN ⊕ QOVR), (QN ⊕ QOVR) + QZ, QZ + $\overline{QC}$ and LOW may also be selected. These functions are useful in testing results of Two's Complement and unsigned number arithmetic operations. The status register may also be tested via the bidirectional T bus. The code to test the status register via T bus is similar to the code used by instruction lines I_1 to I_4 as shown below. Instruction lines I_{0-4} have priority over T bus for testing the status register on CT output. See the discussion on the status register for a full description.

T_4 I_4	T_3 I_3	T_2 I_2	T_1 I_1	CT
0	0	0	0	(N ⊕ OVR) + Z
0	0	0	1	N ⊕ OVR
0	0	1	0	Z
0	0	1	1	OVR
0	1	0	0	LOW*
0	1	0	1	C
0	1	1	0	Z + $\overline{C}$
0	1	1	1	N
1	0	0	0	LINK
1	0	0	1	Flag1
1	0	1	0	Flag2
1	0	1	1	Flag3

*LOW = CT is forced LOW

STATUS

	15	14	13	12	9	8	5	4	0
SETST	0	Quad	1011		1010		Opcode		
RSTST	0	Quad	1010		1010		Opcode		
SVSTR	B/W	Quad	0111		1010		RAM Address/Dest		
SVSTNR	B/W	Quad	0111		1010		Destination		

STATUS INSTRUCTIONS

Instruction	B/W	Quad			Opcode		
SETST	0	11	1011	1010	00011	SONCZ	Set OVR, N, C, Z
					00101	SL	Set LINK
					00110	SF1	Set Flag1
					01001	SF2	Set Flag2
					01010	SF3	Set Flag3
Instruction	**B/W**	**Quad**			**Opcode**		
RSTST	0	11	1010	1010	00011	RONCZ	Reset OVR, N, C, Z
					00101	RL	Reset LINK
					00110	RF1	Reset Flag1
					01001	RF2	Reset Flag2
					01010	RF3	Reset Flag3
Instruction	**B/W**	**Quad**			**RAM Address/Dest**		
SVSTR	0 = B 1 = W	10	0111	1010	00000 .. 11111	R00 .. R31	RAM Reg 00 .... RAM Reg 31
					Destination		
SVSTNR	0 = B 1 = W	11	0111	1010	00000 00001	NRY NRA	Y Bus ACC

STATUS INSTRUCTIONS

Instruction	B/W	Quad			Opcode (CT)		
Test	0	11	1001	1010	00000	TNOZ	Test (N⊕OVR) + Z
					00010	TNO	Test N⊕OVR
					00100	TZ	Test Z
					00110	TOVR	Test OVR
					01000	TLOW	Test LOW
					01010	TC	Test C
					01100	TZC	Test Z + $\overline{C}$
					01110	TN	Test N
					10000	TL	Test LINK
					10010	TF1	Test Flag1
					10100	TF2	Test Flag2
					10110	TF3	Test Flag3

Note: $\overline{EN}$ • test status instruction has priority over T_{1-4} instruction.

Y BUS AND STATUS – FOR STATUS INSTRUCTIONS

Instruction	Opcode	Description	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
SETST	SONCZ	Set OVR, N, C, Z	0 = B	$Y_i \leftarrow 1$ for i = 0 to 15	NC	NC	NC	NC	1	1	1	1
	SL	Set LINK			NC	NC	NC	1	NC	NC	NC	NC
	SF1	Set Flag1			NC	NC	1	NC	NC	NC	NC	NC
	SF2	Set Flag2			NC	1	NC	NC	NC	NC	NC	NC
	SF3	Set Flag3			1	NC	NC	NC	NC	NC	NC	NC
RSTST	RONCZ	Reset OVR, N, C, Z	0 = B	$Y_i \leftarrow 0$ for i = 0 to 15	NC	NC	NC	NC	0	0	0	0
	RL	Reset LINK			NC	NC	NC	0	NC	NC	NC	NC
	RF1	Reset Flag1			NC	NC	0	NC	NC	NC	NC	NC
	RF2	Reset Flag2			NC	0	NC	NC	NC	NC	NC	NC
	RF3	Reset Flag3			0	NC	NC	NC	NC	NC	NC	NC
SVSTR SVSTNR		Save Status*	0 = B 1 = W	$Y_i \leftarrow$ Status for i – 0 to 7; $Y_i \leftarrow 0$ for i = 8 to 15	NC	NC	NC	NC	NC	NC	NC	NC
Test	TNOZ	Test (N⊕OVR) + Z	0 = B	**	NC	NC	NC	NC	NC	NC	NC	NC
	TNO	Test N⊕OVR			NC	NC	NC	NC	NC	NC	NC	NC
	TZ	Test Z			NC	NC	NC	NC	NC	NC	NC	NC
	TOVR	Test OVR			NC	NC	NC	NC	NC	NC	NC	NC
	TLOW	Test LOW			NC	NC	NC	NC	NC	NC	NC	NC
	TC	Test C			NC	NC	NC	NC	NC	NC	NC	NC
	TZC	Test Z + $\overline{C}$			NC	NC	NC	NC	NC	NC	NC	NC
	TN	Test N			NC	NC	NC	NC	NC	NC	NC	NC
	TL	Test LINK			NC	NC	NC	NC	NC	NC	NC	NC
	TF1	Test Flag1			NC	NC	NC	NC	NC	NC	NC	NC
	TF2	Test Flag2			NC	NC	NC	NC	NC	NC	NC	NC
	TF3	Test Flag3			NC	NC	NC	NC	NC	NC	NC	NC

U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified

*In byte mode only the lower byte from the Y bus is loaded into the RAM or ACC and in word mode all 16-bits from the Y bus are loaded into the RAM or ACC.

**Y-Bus is Undefined.

NO-OP INSTRUCTION

The NO-OP Instruction has a fixed 16-bit code. This instruction does not change any internal registers in the Am29C116. It preserves the status register, RAM register and the ACC register.

NO OPERATION FIELD DEFINITION

	15	14	13	12	9	8	5	4	0
NOOP	0		11	1000	1010		00000		

NO-OP INSTRUCTION

Instruction	B/W	Quad			
NOOP	0	11	1000	1010	00000

Y BUS AND STATUS – NO-OP INSTRUCTION

Instruction	Opcode	B/W	Y – Bus	Flag3	Flag2	Flag1	LINK	OVR	N	C	Z
NOOP		0 = B	*	NC	NC	NC	NC	NC	NC	NC	NC

SRC = Source
U = Update
NC = No Change
0 = Reset
1 = Set
i = 0 to 15 when not specified
*Y-Bus is undefined.

SUMMARY OF MNEMONICS

Instruction Type

SOR	Single Operand RAM
SONR	Single Operand Non-RAM
TOR1	Two Operand RAM (Quad 0)
TOR2	Two Operand RAM (Quad 2)
TONR	Two Operand Non-RAM
SHFTR	Single Bit Shift RAM
SHFTNR	Single Bit Shift Non-RAM
ROTR1	Rotate n Bits RAM (Quad 0)
ROTR2	Rotate n Bits RAM (Quad 1)
ROTNR	Rotate n Bits Non-RAM
BOR1	Bit Oriented RAM (Quad 3)
BOR2	Bit Oriented RAM (Quad 2)
BONR	Bit Oriented Non-RAM
ROTM	Rotate and Merge
ROTC	Rotate and Compare
PRT1	Prioritize RAM; Type 1
PRT2	Prioritize RAM; Type 2
PRT3	Prioritize RAM; Type 3
PRTNR	Prioritize Non-RAM
CRCF	Cyclic Redundancy Check Forward
CRCR	Cyclic Redundancy Check Reverse
NOOP	No Operation
SETST	Set Status
RSTST	Reset Status
SVSTR	Save Status RAM
SVSTNR	Save Status Non-RAM
TEST	Test Status

SOURCE AND DESTINATION

Single Operand

SORA	Single Operand RAM to ACC
SORY	Single Operand RAM to Y Bus
SORS	Single Operand RAM to Status
SOAR	Single Operand ACC to RAM
SODR	Single Operand D to RAM
SOIR	Single Operand I to RAM
SOZR	Single Operand 0 to RAM
SOZER	Single Operand D(0E) to RAM
SOSER	Single Operand D(SE) to RAM
SORR	Single Operand RAM to RAM
SOA	Single Operand ACC
SOD	Single Operand D
SOI	Single Operand I
SOZ	Single Operand 0
SOZE	Single Operand D(0E)
SOSE	Single Operand D(SE)
NRY	Non-RAM Y Bus
NRA	Non-RAM ACC
NRS	Non-RAM Status
NRAS	Non-RAM ACC, Status

Two Operand

TORAA	Two Operand RAM, ACC to ACC
TORIA	Two Operand RAM, I to ACC
TODRA	Two Operand D, RAM to ACC
TORAY	Two Operand RAM, ACC to Y Bus
TORIY	Two Operand RAM, I to Y Bus
TODRY	Two Operand D, RAM to Y Bus
TORAR	Two Operand RAM, ACC to RAM
TORIR	Two Operand RAM, I to RAM
TODRR	Two Operand D, RAM to RAM
TODAR	Two Operand D, ACC to RAM
TOAIR	Two Operand ACC, I to RAM
TODIR	Two Operand D, I to RAM
TODA	Two Operand D, ACC
TOAI	Two Operand ACC, I
TODI	Two Operand D, I

Single Bit Shift

SHRR	Shift RAM, Store in RAM
SHDR	Shift D, Store in RAM
SHA	Shift ACC
SHD	Shift D

Rotate n Bits

RTRA	Rotate RAM, Store in ACC
RTRY	Rotate RAM, Place on Y Bus
RTRR	Rotate RAM, Store in RAM
RTAR	Rotate ACC, Store in RAM
RTDR	Rotate D, Store in RAM
RTDY	Rotate D, Place on Y Bus
RTDA	Rotate D, Store in ACC
RTAY	Rotate ACC, Place on Y Bus
RTAA	Rotate ACC, Store in ACC

Rotate and Merge

MDAI	Merge Disjoint Bits of D and ACC Using I as Mask and Store in ACC
MDAR	Merge Disjoint Bits of D and ACC Using RAM as Mask and Store in ACC
MDRI	Merge Disjoint Bits of D and RAM Using I as Mask and Store in RAM
MDRA	Merge Disjoint Bits of D and RAM Using ACC as Mask and Store in RAM
MARI	Merge Disjoint Bits of ACC and RAM Using I as Mask and Store in RAM
MRAI	Merge Disjoint Bits of RAM and ACC Using I as Mask and Store in ACC

Rotate and Compare

CDAI	Compare Unmasked Bits of D and ACC Using I as Mask

CDRI	Compare Unmasked Bits of D and RAM Using I as Mask
CDRA	Compare Unmasked Bits of D and RAM Using ACC as Mask
CRAI	Compare Unmasked Bits of RAM and ACC Using I as Mask

Prioritize

PR1A	ACC as Destination for Prioritize Type 1
PR1Y	Y Bus as Destination for Prioritize Type 1
PR1R	RAM as Destination for Prioritize Type 1
PRT1A	ACC as Source for Prioritize Type 1
PR1D	D as Source for Prioritize Type 1
PR2A	ACC as Destination for Prioritize Type 2
PR2Y	Y Bus as Destination for Prioritize Type 2
PR3R	RAM as Source for Prioritize Type 3
PR3A	ACC as Source for Prioritize Type 3
PR3D	D as Source for Prioritize Type 3
PRTA	ACC as source for Prioritize Type Non-RAM
PRTD	D as Source for Prioritize Type Non-RAM
PRA	ACC as Mask for Prioritize Type 2, 3, and Non-RAM
PRZ	Mask Equal to Zero for Prioritize Type 2, 3, and Non-RAM
PRI	I as Mask for Prioritize Type 2, 3, and Non-RAM

OPCODE

Addition

ADD	Add without Carry
ADDC	Add with Carry
A2NA	Add 2^n to ACC
A2NR	Add 2^n to RAM
A2NDY	Add 2^n to D, Place on Y Bus

Subtraction

SUBR	Subtract R from S without Carry
SUBRC	Subtract R from S with Carry
SUBS	Subtract S from R without Carry
SUBSC	Subtract S from R with Carry
S2NR	Subtract 2^n from RAM
S2NA	Subtract 2^n from ACC
S2NDY	Subtract 2^n from D, Place on Y Bus

Logical Operations

AND	Boolean AND
NAND	Boolean NAND
EXOR	Boolean EXOR
NOR	Boolean NOR
OR	Boolean OR
EXNOR	Boolean EXNOR

SHIFTS

SHUPZ	Shift Up Towards MSB with 0 Insert
SHUP1	Shift Up Towards MSB with 1 Insert
SHUPL	Shift Up Towards MSB with LINK Insert
SHDNZ	Shift Down Towards LSB with 0 Insert
SHDN1	Shift Down Towards LSB with 1 Insert
SHDNL	Shift Down Towards LSB with LINK Insert
SHDNC	Shift Down Towards LSB with Carry Insert
SHDNOV	Shift Down Towards LSB with Sign EXOR Overflow Insert

Loads

LD2NR	Load 2^n into RAM
LDC2NR	Load $\overline{2^n}$ into RAM
LD2NA	Load 2^n into ACC
LDC2NA	Load $\overline{2^n}$ into ACC
LD2NY	Place 2^n on Y Bus
LDC2NY	Place $\overline{2^n}$ on Y Bus

Bit Oriented

SETNR	Set RAM, Bit n
SETNA	Set ACC, Bit n
SETND	Set D, Bit n
SONCZ	Set OVR, N, C, Z, in Status Register
SL	Set LINK Bit in Status Register
SF1	Set Flag1 Bit in Status Register
SF2	Set Flag2 Bit in Status Register
SF3	Set Flag3 Bit in Status Register
RSTNR	Reset RAM, Bit n
RSTNA	Reset ACC, Bit n
RSTND	Reset D, Bit n
RONCZ	Reset OVR, N, C, Z, in Status Register
RL	Reset LINK Bit in Status Register
RF1	Reset Flag1 Bit in Status Register
RF2	Reset Flag2 Bit in Status Register
RF3	Reset Flag3 Bit in Status Register
TSTNR	Test RAM, Bit n
TSTNA	Test ACC, Bit n
TSTND	Test D, Bit n

Arithmetic Operations

MOVE	Move and Update Status
COMP	Complement (1's Complement)
INC	Increment
NEG	Two's Complement

Conditional Test

TNOZ	Test (N $\oplus$ OVR) + Z
TNO	Test N $\oplus$ OVR
TZ	Test Zero Bit
TOVR	Test Overflow Bit
TLOW	Test for LOW
TC	Test Carry Bit
TZC	Test Z + $\overline{C}$
TN	Test Negative Bit
TL	Test LINK Bit
TF1	Test Flag1 Bit
TF2	Test Flag2 Bit
TF3	Test Flag3 Bit

APPLICATIONS

Minimum System Cycle Time Calculations for the Am29C116

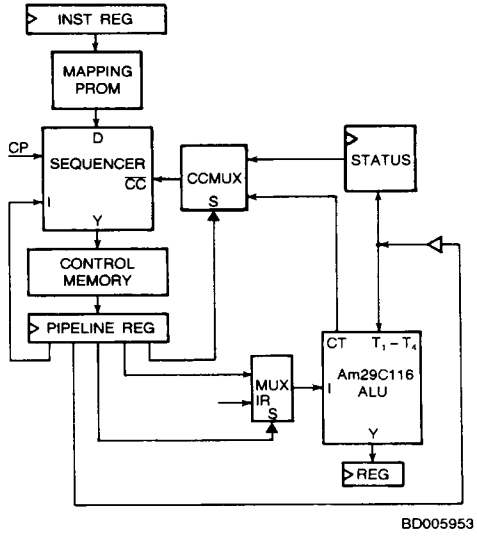


Figure 15. System Block Diagram

DATA PATH TIMING ANALYSIS

				29C116	29C116-1	29C116-2
I.	**Without Any External Logic**					
a.	Pipeline Register		CP–Q	12 ns	12 ns	12 ns
	RALU	(29C116)	I–T	84	73	60
	Status Register		Setup	4	4	4
	Cycle Time:			**100 ns**	**89 ns**	**76 ns**
b.	Pipeline Register		CP–Q	12 ns	12 ns	12 ns
	RALU	(29C116)	I–Y	79	65	57
	Data Register		Setup	4	4	4
	Cycle Time:			**95 ns**	**81 ns**	**73 ns**
II.	**With Multiplexers for Address, N–Count, etc.**					
a.	Pipeline Register		CP–Q	12 ns	12 ns	12 ns
	Multiplexer		Sel–Y	15	15	15
	RALU	(29C116)	I–T	84	73	60
	Status Register		Setup	4	4	4
	Cycle Time:			**115 ns**	**104 ns**	**91 ns**
b.	Pipeline Register		CP–Q	12 ns	12 ns	12 ns
	Multiplexer		Sel–Y	15	15	15
	RALU	(29C116)	I–Y	79	65	57
	Data Register		Setup	4	4	4
	Cycle Time:			**110 ns**	**96 ns**	**88 ns**

The Use of an External Status Register in Reducing Microcycle Length

The standard connection of the CT pin of the Am29C116 and microcycle length calculation arising from that connection are shown below:

CRITICAL PATH TIMING (FIGURE 16-1)

Part Number	Path	Maximum Commercial Delay (ns)
Pipeline Register	CP–Q	12
Am29C116-2	I, T–CT	25
CC–MUX	D–W	7
Am29C10A-1	CC–Y	26
Control Memory	t_{AA}	40
Pipeline Register	Setup	4
		114

While 114-ns cycle time is quite fast, it can be improved by using an external register for status testing.

CRITICAL PATH TIMING (FIGURE 16-2)

Part Number	Path	Maximum Commercial Delay (ns)
Status Reg	CP–Y	12
CC–MUX	Sel–W	15
Am29C10A-1	CC–Y	26
Control Memory	t_{AA}	40
Pipeline Register	Setup	4
		97

The cycle time has been reduced from 114 ns to 97 ns.

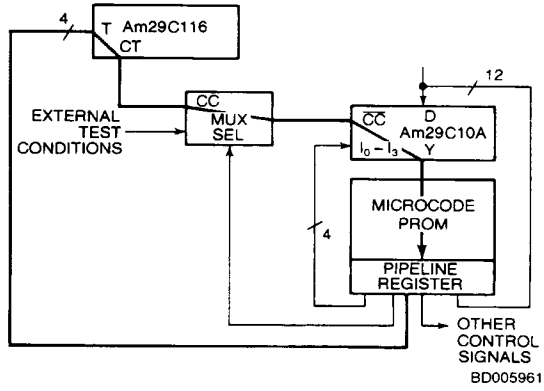


Figure 16-1.

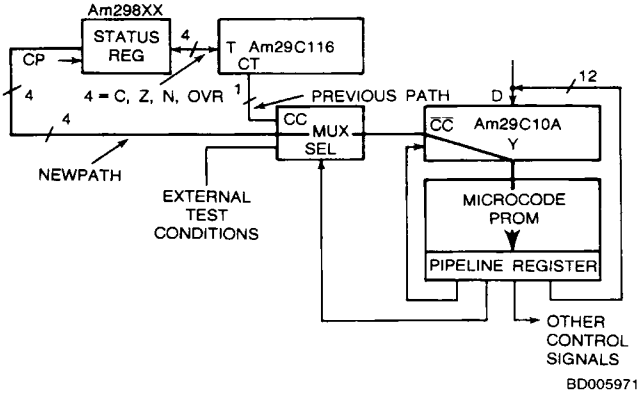


Figure 16-2.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature ..... −65 to +150°C
(Case) Temperature Under Bias ..... −55 to +125°C
Supply Voltage to
Ground Potential Continuous ..... −0.3 V to +7.0 V
DC Voltage Applied to Outputs For
High Output State ..... −0.3 V to +V_{CC} +0.3 V
DC Input Voltage ..... −0.3 V to +V_{CC} +0.3 V
DC Output Current, Into LOW Outputs ..... 30 mA
DC Input Current ..... −10 mA to +10 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices
Ambient Temperature (T_A) ..... 0 to +70°C
Supply Voltage (V_{CC}) ..... +4.5 V to +5.5 V

Military* (M) Devices
Ambient Temperature (T_A) ..... −55 to +125°C
Supply Voltage (V_{CC}) ..... +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

*Military Product 100% tested at T_A = +25°C, +125°C, and −55°C.

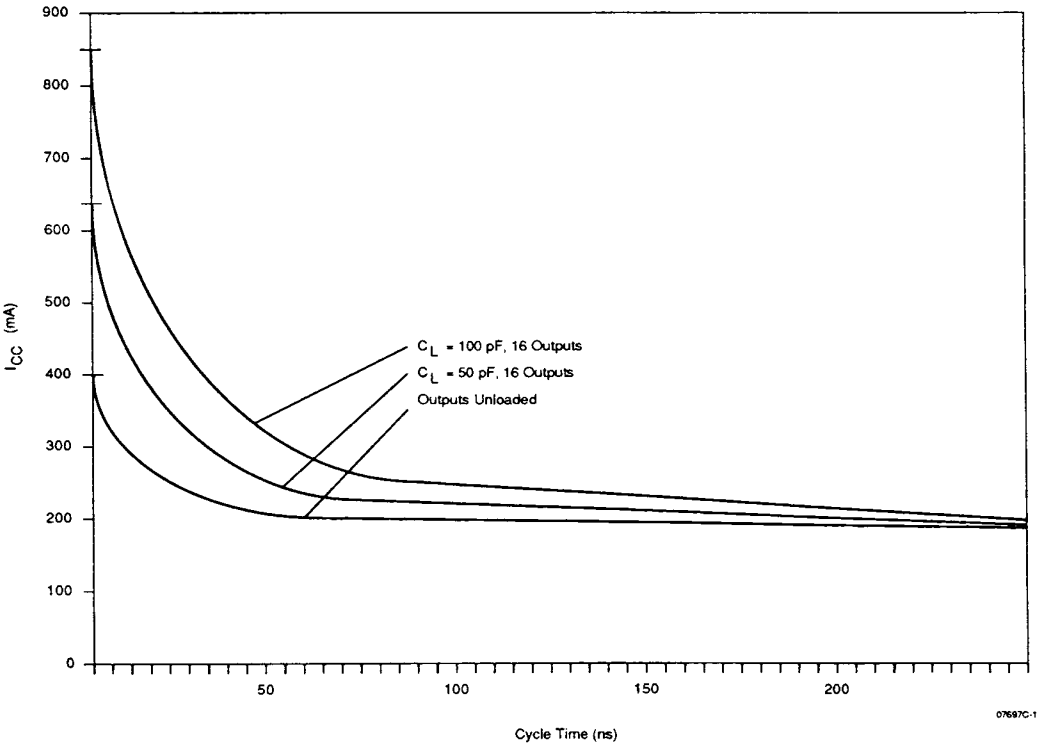
DC CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test Conditions (Note 1)			Min.	Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC} = Min. V_{IN} = V_{IH} or V_{IL}		I_{OH} = −1.6 mA/−1.2 mA (COM'L/MIL)	2.4		V
V_{OL}	Output LOW Voltage	V_{CC} = Min. V_{IN} = V_{IH} or V_{IL}		I_{OL} = 16 mA/12 mA (COM'L/MIL)		0.5	V
V_{IH}	Guaranteed Input Logical HIGH Voltage (Note 2)				2.0		V
V_{IL}	Guaranteed Input Logical LOW Voltage (Note 2)					0.8	V
I_{IL}	Input LOW Current	V_{CC} = Max. V_{IN} = 0.5 Volts				−10	μA
I_{IH}	Input HIGH Current	V_{CC} = Max. V_{IN} = V_{CC} − 0.5 V				10	μA
I_{OZH}	Off State (HIGH Impedance) Output Current	V_{CC} = Max. V_O = 2.4 Volts				10	μA
I_{OZL}	Off State (HIGH Impedance) Output Current	V_{CC} = Max. V_O = 0.5 Volts				−10	μA
I_{CC}	Static Power Supply Current (Note 3)	V_{CC} = Max. I_O = 0 μA	COM'L T_A = 0 to +70°C	(Note 4) CMOS V_{IN} = V_{CC} or GND		120	mA
				(Note 4) TTL V_{IN} = 0.5 V or 2.4 V		170	
			MIL T_A = −55 to +125°C	(Note 4) CMOS V_{IN} = V_{CC} or GND		145	
				(Note 4) TTL V_{IN} = 0.5 V or 2.4 V		200	
C_{PD}	Power Dissipation Capacitance (Note 5)	V_{CC} = 5.0 V T_A = 25°C No Load			850 pF Typical		

Notes: 1. V_{CC} conditions shown as Min. or Max. refer to ±10% V_{CC} limits.
2. These input levels provide zero-noise immunity and should only be statically tested in a noise-free environment (not functionally tested).
3. Worst-case I_{CC} is measured at the lowest temperature in the specified operating range.
4. Use CMOS I_{CC} when the device is driven by CMOS circuits and TTL I_{CC} when the device is driven by TTL circuits.
5. C_{PD} determines the dynamic current consumption:

$$I_{CC}\ (\text{Total}) = I_{CC}\ (\text{Static}) + (C_{PD} + nCL)\frac{f}{2},$$ where f is the clock frequency, CL output load capacitance, and n number of loads.

29C116 I_{CC} vs Cycle Time



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Note: Values are calculated as typical total I_{CC} at V_{CC} = 5.5 V.

SWITCHING CHARACTERISTICS over **COMMERCIAL** operating range unless otherwise specified (T_A = 0 to +70°C, V_{CC} = 4.5 to 5.5 V, C_L = 50 pF)

Am29C116

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	79	84	–
I_{0-15} (DATA)	79	84	–
I_{0-15} (INSTR)	79	84	48
DLE	58*	60	–
T_{1-4}	–	–	39
CP	63	66	40
Y_{0-15}	62*	64	–
$\overline{IEN}$	–	–	43

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: C_L = 5 pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	22	22	22	22
OE_T	T_{1-4}	25	25	25	25

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	20	30
DLE	–	15
$\overline{IEN}$	22	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment	
		Setup	Hold	Setup	Hold		
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 24	(t_{h1}) 0	–	–	Single ADDR (Source)	
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 5	–	–	(t_{h7}) 2	Two ADDR (Destination)	
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 65	(t_{h8}) 0		
I_{0-15} (INSTR)	CP	(t_{s3}) 38	(t_{h3}) 17	(t_{s9}) 65	(t_{h9}) 2		
$\overline{IEN}$ HIGH	CP	(t_{s4}) 10	–	–	(t_{h10}) 2	Disable	
$\overline{IEN}$ LOW	CP	– | (t_{s5}) 20	– | (t_{h5}) 1	(t_{s11}) 22 | –	(t_{h11}) 1** | –	Enable	Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 17	(t_{h12}) 0		
Y	CP	–	–	(t_{s13}) 44	(t_{h13}) 0		
Y	DLE	(t_{s6}) 10	(t_{h6}) 6	–	–		
DLE	CP	–	–	(t_{s14}) 45	(t_{h14}) 0		

** Status register and accumulator destination only.

SWITCHING CHARACTERISTICS over COMMERCIAL operating range (Cont'd.)

Am29C116-1

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	65	73	–
I_{0-15} (DATA)	65	73	–
I_{0-15} (INSTR)	65	73	30
DLE	55*	55	–
T_{1-4}	–	–	27
CP	60	66	37
Y_{0-15}	53*	53	–
$\overline{IEN}$	–	–	25

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: C_L = 5 pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	22	22	22	22
OE_T	T_{1-4}	22	22	22	22

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	20	30
DLE	–	15
$\overline{IEN}$	20	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment	
		Setup	Hold	Setup	Hold		
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 13	(t_{h1}) 0	–	–	Single ADDR (Source)	
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 5	–	–	(t_{h7}) 0	Two ADDR (Destination)	
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 60	(t_{h8}) 0		
I_{0-15} (INSTR)	CP	(t_{s3}) 24	(t_{h3}) 12	(t_{s9}) 60	(t_{h9}) 0		
$\overline{IEN}$ HIGH	CP	(t_{s4}) 5	–	–	(t_{h10}) 2	Disable	
$\overline{IEN}$ LOW	CP	– / (t_{s5}) 5	– / (t_{h5}) 1	(t_{s11}) 10 / –	(t_{h11}) 1** / –	Enable	Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 12	(t_{h12}) 0		
Y	CP	–	–	(t_{s13}) 42	(t_{h13}) 0		
Y	DLE	(t_{s6}) 6	(t_{h6}) 5	–	–		
DLE	CP	–	–	(t_{s14}) 43	(t_{h14}) 0		

** Status register and accumulator destination only.

SWITCHING CHARACTERISTICS over COMMERCIAL operating range

Am29C116-2

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	57	60	–
I_{0-15} (DATA)	57	60	–
I_{0-15} (INSTR)	57	60	25
DLE	45*	45	–
T_{1-4}	–	–	25
CP	50	55	29
Y_{0-15}	45*	45	–
$\overline{IEN}$	–	–	25

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: C_L = 5 pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	22	22	22	22
OE_T	T_{1-4}	22	22	22	22

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	20	30
DLE	–	15
$\overline{IEN}$	20	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment
		Setup	Hold	Setup	Hold	
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 13	(t_{h1}) 0	–	–	Single ADDR (Source)
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 5	–	–	(t_{h7}) 0	Two ADDR (Destination)
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 50	(t_{h8}) 0	
I_{0-15} (INSTR)	CP	(t_{s3}) 22	(t_{h3}) 10	(t_{s9}) 50	(t_{h9}) 0	
$\overline{IEN}$ HIGH	CP	(t_{s4}) 5	–	–	(t_{h10}) 2	Disable
$\overline{IEN}$ LOW	CP	– | (t_{s5}) 5	– | (t_{h5}) 1	(t_{s11}) 10 | –	(t_{h11}) 1** | –	Enable | Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 12	(t_{h12}) 0	
Y	CP	–	–	(t_{s13}) 39	(t_{h13}) 0	
Y	DLE	(t_{s6}) 6	(t_{h6}) 5	–	–	
DLE	CP	–	–	(t_{s14}) 43	(t_{h14}) 0	

** Status register and accumulator destination only.

SWITCHING CHARACTERISTICS over **MILITARY** operating range (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted) ($T_A = -55$ to $+125°C$, $V_{CC} = 4.5$ to 5.5 V, $C_L = 50$ pF).

Am29C116

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	100	103	–
I_{0-15} (DATA)	100	103	–
I_{0-15} (INSTR)	100	103	50
DLE	68*†	70	–
T_{1-4}	–	–	46
CP	76	83	48
Y_{0-15}	70*†	72	–
$\overline{IEN}$	–	–	50

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: $C_L = 5$ pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	25	25	25	25
OE_T	T_{1-4}	30	30	30	30

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	33	50
DLE	–	20
$\overline{IEN}$	33	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment	
		Setup	Hold	Setup	Hold		
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 24	(t_{h1}) 1	–	–	Single ADDR (Source)	
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 10	–	–	(t_{h7}) 3	Two ADDR (Destination)	
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 78	(t_{h8}) 3		
I_{0-15} (INSTR)	CP	(t_{s3}) 57	(t_{h3}) 17	(t_{s9}) 78	(t_{h9}) 3		
$\overline{IEN}$ HIGH	CP	(t_{s4}) 10	–	–	(t_{h10}) 2	Disable	
$\overline{IEN}$ LOW	CP	– (t_{s5}) 20	– (t_{h5}) 3	(t_{s11}) 28 –	(t_{h11}) 3** –	Enable	Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 19	(t_{h12}) 1		
Y	CP	–	–	(t_{s13}) 53	(t_{h13}) 2		
Y	DLE	(t_{s6}) 11	(t_{h6}) 7	–	–		
DLE	CP	–	–	(t_{s14}) 54	(t_{h14}) 0		

**Status register and accumulator destination only.

† Not included in Group A tests.

SWITCHING CHARACTERISTICS over **MILITARY** operating range (Cont'd.)

Am29C116-1

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	75	75	–
I_{0-15} (DATA)	75	75	–
I_{0-15} (INSTR)	75	75	29
DLE	62*†	62	–
T_{1-4}	–	–	29
CP	67	75	39
Y_{0-15}	60*†	60	–
$\overline{IEN}$	–	–	29

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: C_L = 5 pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	25	25	20	20
OE_T	T_{1-4}	25	25	16	16

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	25	15
DLE	–	15
$\overline{IEN}$	15	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment	
		Setup	Hold	Setup	Hold		
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 12	(t_{h1}) 1	–	–	Single ADDR (Source)	
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 7	–	–	(t_{h7}) 0	Two ADDR (Destination)	
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 65	(t_{h8}) 0		
I_{0-15} (INSTR)	CP	(t_{s3}) 27	(t_{h3}) 12	(t_{s9}) 65	(t_{h9}) 2		
$\overline{IEN}$ HIGH	CP	(t_{s4}) 5	–	–	(t_{h10}) 2	Disable	
$\overline{IEN}$ LOW	CP	– (t_{s5}) 7	– (t_{h5}) 3	(t_{s11}) 12 –	(t_{h11}) 3** –	Enable	Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 12	(t_{h12}) 1		
Y	CP	–	–	(t_{s13}) 53	(t_{h13}) 0		
Y	DLE	(t_{s6}) 7	(t_{h6}) 3	–	–		
DLE	CP	–	–	(t_{s14}) 54	(t_{h14}) 0		

**Status register and accumulator destination only.

† Not included in Group A tests.

SWITCHING CHARACTERISTICS over **MILITARY** operating range (Cont'd.)

Am29C116-2

A. Combinational Delays (nsec)

Input	Outputs		
	Y_{0-15}	T_{1-4}	CT
I_{0-4} (ADDR)	65	65	–
I_{0-15} (DATA)	65	65	–
I_{0-15} (INSTR)	65	65	26
DLE	52*†	52	–
T_{1-4}	–	–	26
CP	57	65	33
Y_{0-15}	52*†	52	–
$\overline{IEN}$	–	–	26

Y_{0-15} must be stored in the Data Latch and its source disabled before the delay to Y_{0-15} as an output can be measured.
*Guaranteed indirectly by other tests.

B. Enable/Disable Times (nsec)
(Disable: C_L = 5 pF, 0.5-V Change on Outputs)

From Input	To Output	Enable		Disable	
		t_{PZH}	t_{PZL}	t_{PHZ}	t_{PLZ}
$\overline{OE}_Y$	Y_{0-15}	22	22	18	18
OE_T	T_{1-4}	22	22	15	15

C. Clock and Pulse Requirements (nsec)

Input	Min. LOW Time	Min. HIGH Time
CP	20	15
DLE	–	15
$\overline{IEN}$	15	–

D. Setup and Hold Times (nsec)

Input	With Respect to	HIGH-to-LOW Transition		LOW-to-HIGH Transition		Comment	
		Setup	Hold	Setup	Hold		
I_{0-4} (RAM ADDR)	CP	(t_{s1}) 12	(t_{h1}) 1	–	–	Single ADDR (Source)	
I_{0-4} (RAM ADDR)	CP and $\overline{IEN}$ both LOW	(t_{s2}) 7	–	–	(t_{h7}) 0	Two ADDR (Destination)	
I_{0-15} (DATA)	CP	–	–	(t_{s8}) 56	(t_{h8}) 0		
I_{0-15} (INSTR)	CP	(t_{s3}) 25	(t_{h3}) 12	(t_{s9}) 56	(t_{h9}) 2		
$\overline{IEN}$ HIGH	CP	(t_{s4}) 5	–	–	(t_{h10}) 2	Disable	
$\overline{IEN}$ LOW	CP	– / (t_{s5}) 7	– / (t_{h5}) 3	(t_{s11}) 10 / –	(t_{h11}) 3** / –	Enable	Immediate first cycle
$\overline{SRE}$	CP	–	–	(t_{s12}) 10	(t_{h12}) 1		
Y	CP	–	–	(t_{s13}) 45	(t_{h13}) 0		
Y	DLE	(t_{s6}) 7	(t_{h6}) 3	–	–		
DLE	CP	–	–	(t_{s14}) 46	(t_{h14}) 0		

**Status register and accumulator destination only.

† Not included in Group A tests.

Test Philosophy and Methods

The following points give the general philosophy that we apply to tests that must be properly engineered if they are to be implemented in an automatic environment. The specifics of what philosophies applied to which test are shown in the data sheet.

1. Ensure the part is adequately decoupled at the test head. Large changes in V_{CC} current as the device switches may cause erroneous function failures due to V_{CC} changes.
2. Do not leave inputs floating during any tests, as they may start to oscillate at high frequency.
3. Do not attempt to perform threshold tests at high speed. Following an output transition, ground current may change by as much as 400 mA in 5-8 ns. Inductance in the ground cable may allow the ground pin at the device to rise by hundreds of millivolts momentarily. Current level may vary from product to product.
4. Use extreme care in defining input levels for AC tests. Many inputs may be changed at once, so there will be significant noise at the device pins that may not actually reach V_{IL} or V_{IH} until the noise has settled. AMD recommends using $V_{IL} \leqslant 0$ V and $V_{IH} \geqslant 3.0$ V for AC tests.
5. To simplify failure analysis, programs should be designed to perform DC, Function, and AC tests as three distinct groups of tests.
6. Capacitive Loading for AC Testing

   Automatic testers and their associated hardware have stray capacitance that varies from one type of tester to another but is generally around 50 pF. This makes it impossible to make direct measurements of parameters that call for a smaller capacitive load than the associated stray capacitance. Typical examples of this are the so-called "float delays," which measure the propagation delays into the high-impedance state and are usually specified at a load capacitance of 5.0 pF. In these cases, the test is performed at the higher load capacitance (typically 50 pF), and engineering correlations based on data taken with a bench set up are used to predict the result at the lower capacitance.

   Similarly, a product may be specified at more than one capacitive load. Since the typical automatic tester is not capable of switching loads in mid-test, it is impossible to make measurements at both capacitances even though they may both be greater than the stray capacitance. In these cases, a measurement is made at one of the two capacitances. The result at the other capacitance is predicted from engineering correlations based on data taken with a bench setup and the knowledge that certain DC measurements (I_{OH}, I_{OL}, for example) have already been taken and are within specification. In some cases, special DC tests are performed in order to facilitate this correlation.
7. Threshold Testing

   The noise associated with automatic testing (due to the long inductive cables), and the high gain of the tested device when in the vicinity of the actual device threshold, frequently give rise to oscillations when testing high-speed circuits. These oscillations are not indicative of a reject device, but instead, of an overtaxed test system. To minimize this problem, thresholds are tested at least once for each input pin. Thereafter, "hard" high and low levels are used for other tests. Generally this means that function and AC testing are performed at "hard" input levels rather than at V_{IL} Max. and V_{IH} Min.
8. AC Testing

   Occasionally parameters are specified that cannot be measured directly on automatic testers because of tester limitations. Data input hold times often fall into this category. In these cases, the parameter in question is guaranteed by correlating these tests with other AC tests that have been performed. These correlations are arrived at by the cognizant engineer using data from precise bench measurements in conjunction with the knowledge that certain DC parameters have already been measured and are within spec.

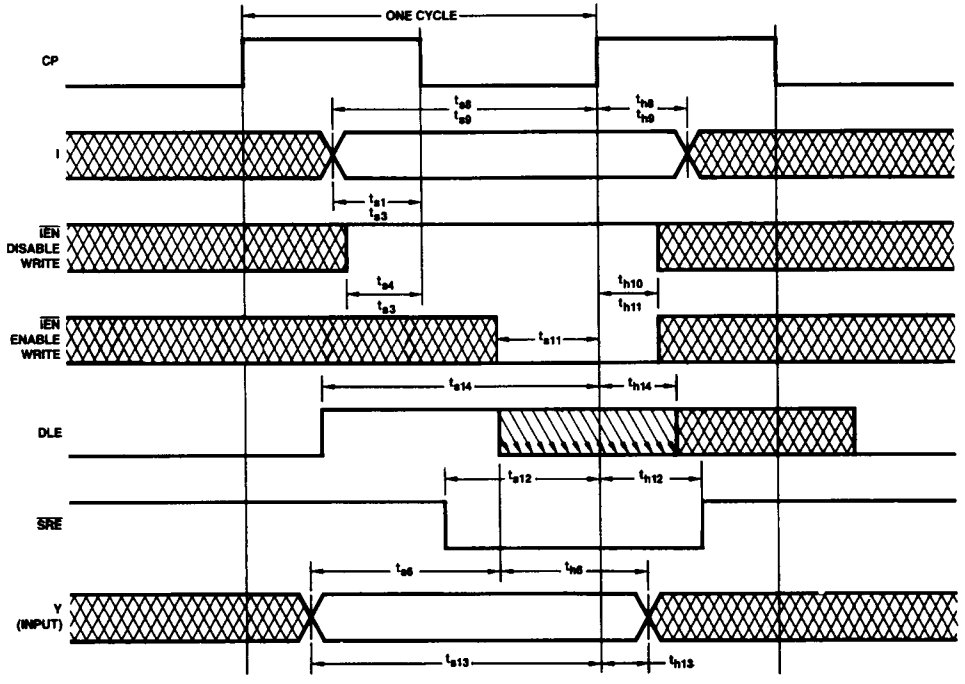
   In some cases, certain AC tests are redundant since they can be shown to be predicted by other tests that have already been performed. In these cases, the redundant tests are not performed.

SWITCHING WAVEFORMS

KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	MUST BE STEADY	WILL BE STEADY
	MAY CHANGE FROM H TO L	WILL BE CHANGING FROM H TO L
	MAY CHANGE FROM L TO H	WILL BE CHANGING FROM L TO H
	DON'T CARE; ANY CHANGE PERMITTED	CHANGING; STATE UNKNOWN
	DOES NOT APPLY	CENTER LINE IS HIGH IMPEDANCE "OFF" STATE

KS000010

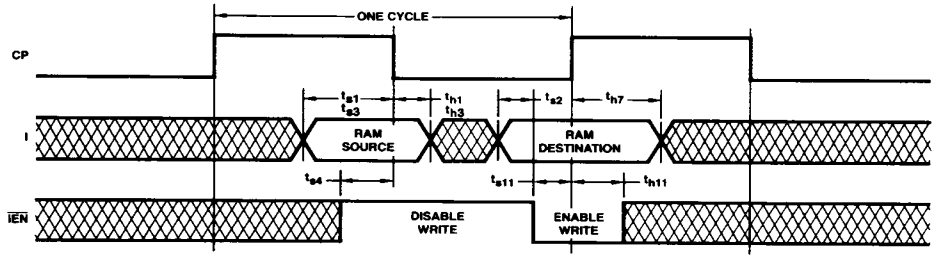


WF002563

Single-Address Access Timing

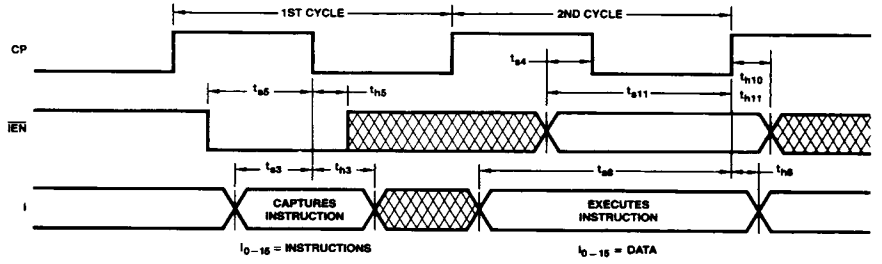
If t_{h6} is satisfied, t_{h13} need not be satisfied.

SWITCHING WAVEFORMS (Cont'd.)



WF002545

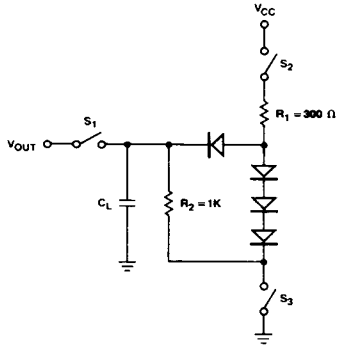
Double Address Access Timing



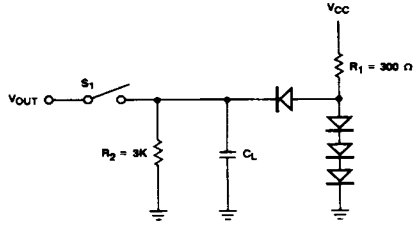
WF002550

Immediate Instruction Cycle Timing

SWITCHING TEST CIRCUITS



TCR01331

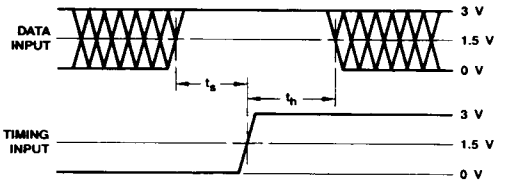


TC000421

A. Three-State Outputs **B. Normal Outputs**

Notes: 1. C_L = 50 pF includes scope probe, wiring and stray capacitances without device in test fixture.
2. S_1, S_2, S_3 are closed during function tests and all AC tests except output enable tests.
3. S_1 and S_3 are closed while S_2 is open for t_{PZH} test.
S_1 and S_2 are closed while S_3 is open for t_{PZL} test.
4. C_L = 5.0 pF for output disable tests.

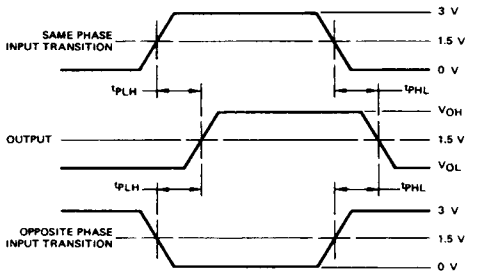
SWITCHING TEST WAVEFORMS



WFR02970

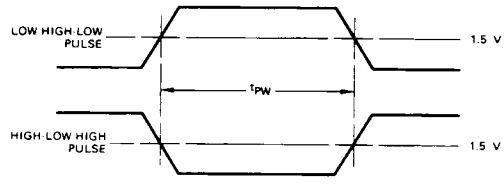
Notes: 1. Diagram shown for HIGH data only.
Output transition may be opposite sense.
2. Cross hatched area is don't care condition.

Setup, Hold, and Release Times



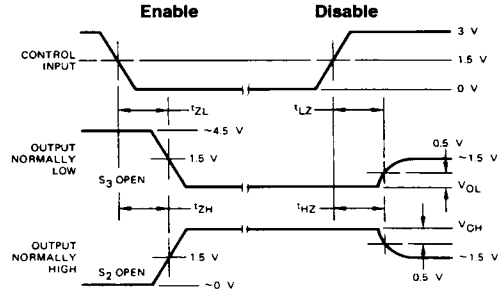
WFR02980

Propagation Delay



WFR02790

Pulse Width

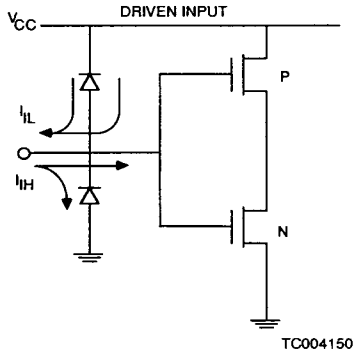


WFR02660

Notes: 1. Diagram shown for Input Control Enable-LOW and Input Control Disable-HIGH.
2. S_1, S_2 and S_3 of Load Circuit are closed except where shown.

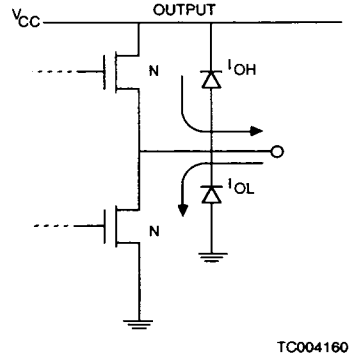
Enable and Disable Times

INPUT/OUTPUT CIRCUIT DIAGRAMS



TC004150

$C_I \approx 5.0$ pF, all inputs

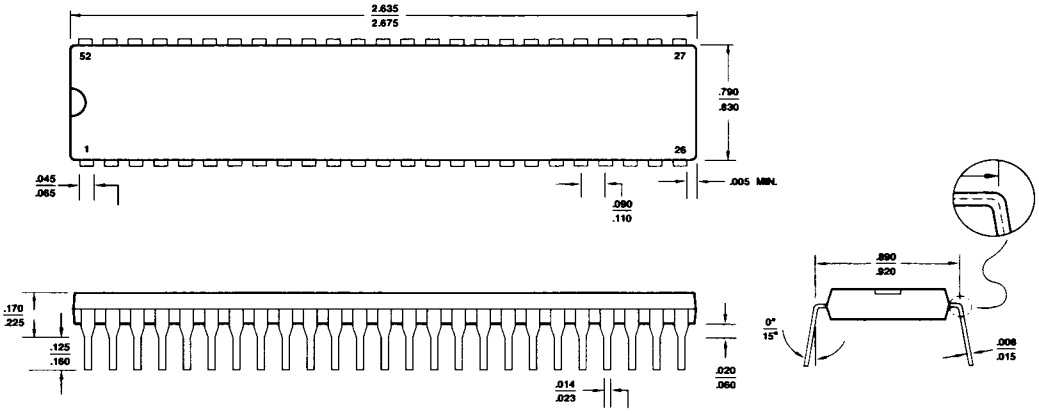


TC004160

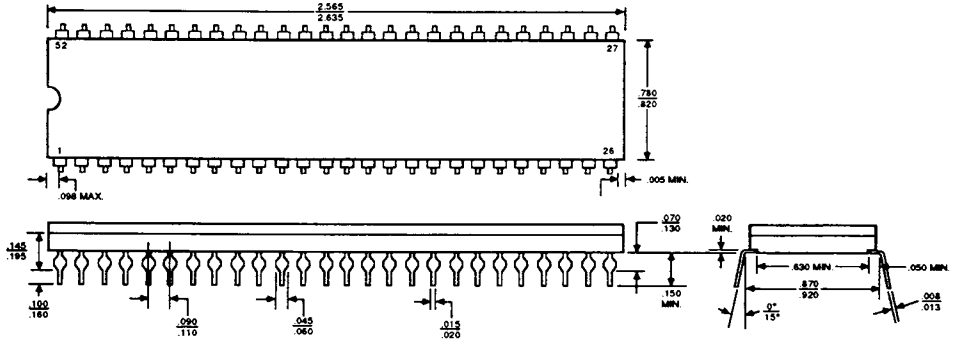
$C_O \approx 5.0$ pF, all outputs

PHYSICAL DIMENSIONS*

PD 052



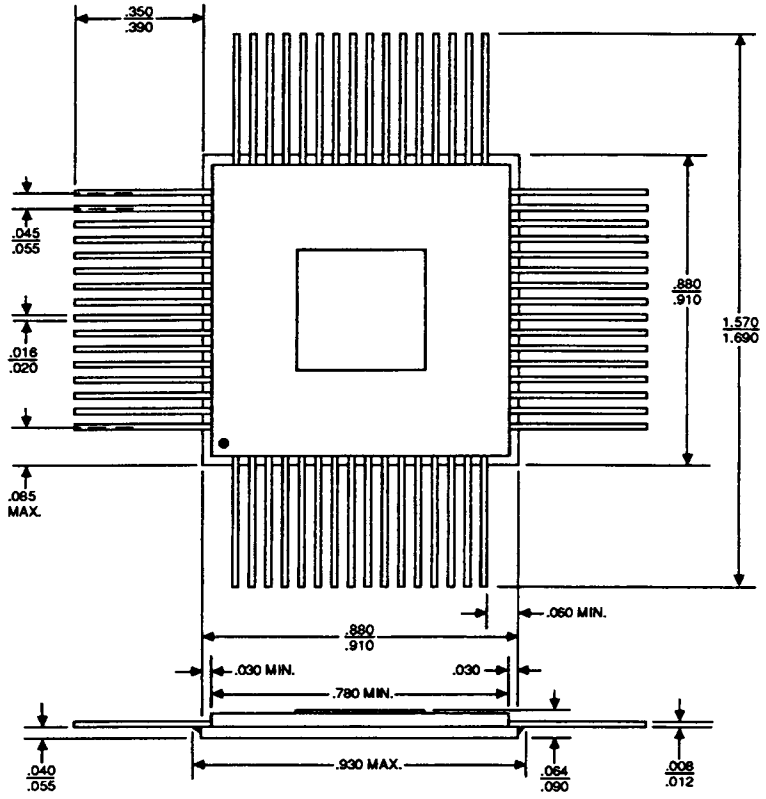
TDX052



*For reference only.

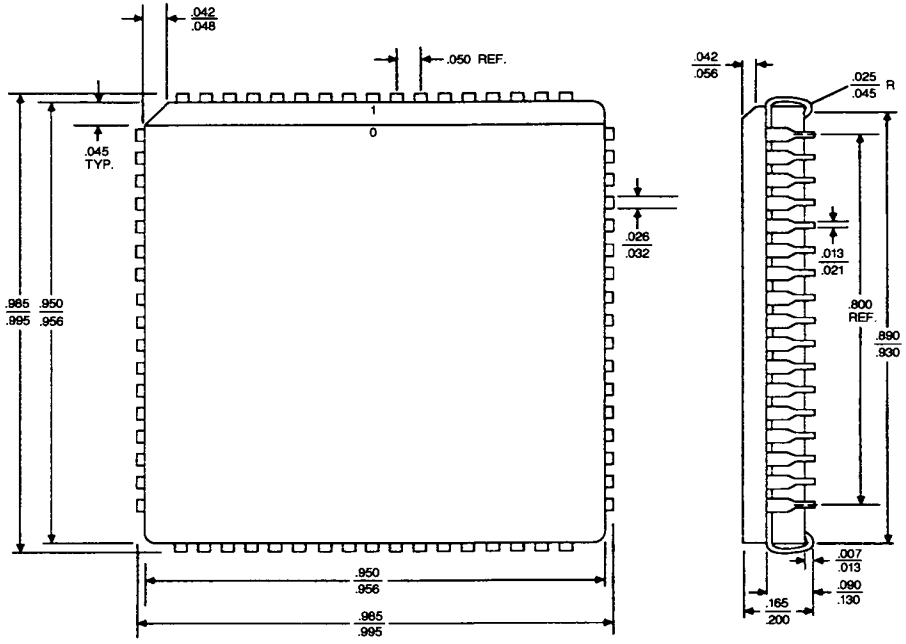
PHYSICAL DIMENSIONS (Cont'd.)

CFT064



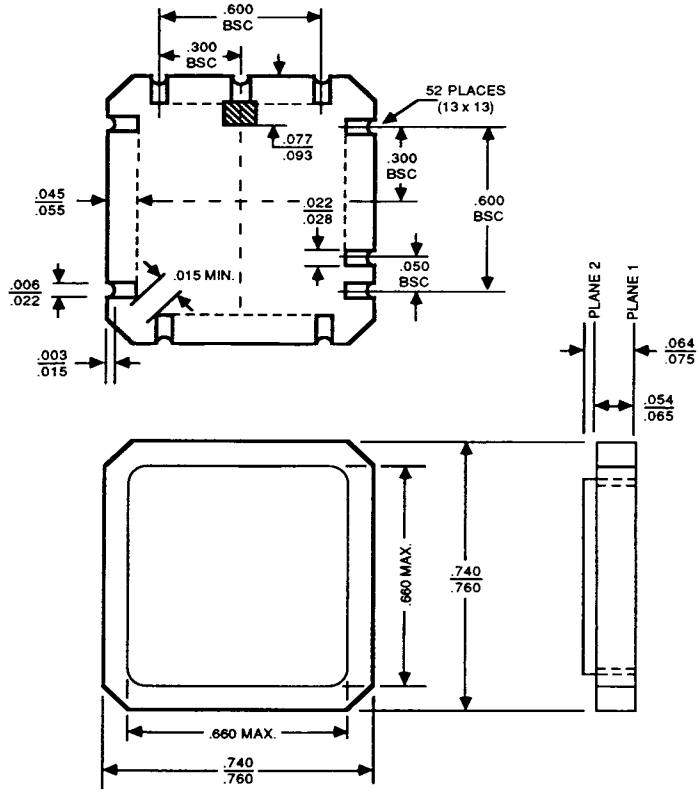
PHYSICAL DIMENSIONS (Cont'd.)

PL 068



PHYSICAL DIMENSIONS (Cont'd.)

CLT052



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